

TEST REPORT

Applicant Name: Shenzhen Minew Technologies Co., Ltd.
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Science Park, No. 6 QingLong Road, Qinghua Community,
Longhua District, Shenzhen
Report Number: 2501Y11127E-RF-07A

Test Standard (s)

Item 19 of Article 2 Paragraph 1

Sample Description

Product Type: Industrial Temperature and Humidity Sensor
Model No.: MST01
Multiple Model(s) No.: N/A
Trade Mark: MINEW
Date Received: 2025-10-23
Issue Date: 2025-11-21

Test Result:	Pass▲
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▲ In the configuration tested, the EUT complied with the standards above.

Prepared and Checked By:

Gal La Liu

GalLa Liu
RF Engineer

Approved By:

Nancy Wang

Nancy Wang
RF Supervisor

Note: The information marked * is provided by the applicant, the laboratory is not responsible for its authenticity and this information can affect the validity of the result in the test report. Customer model name, addresses, names, trademarks etc. are included.

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Bay Area Compliance Laboratories Corp. (Shenzhen)

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DOCUMENT REVISION HISTORY

Revision Number	Report Number	Description of Revision	Date of Revision
0	2501Y11127E-RF-07A	Original Report	2025-11-21

GENERAL INFORMATION

Product Description for Equipment under Test (EUT)

Technical Parameters	Radio Type	BLE
	Modulation Type	GFSK
	Frequency Range	2402-2480MHz
	Rated Output Power	2mW for BLE 1M;2 mW for BLE 2M
	Antenna Gain[#]	3.47 dBi (It is provided by the applicant)
Nominal Power Supply		Lithium -Thionyl Chloride battery DC 3.6V
Sample serial number		3BRX-2 (Assigned by BACL, Shenzhen)
Sample/EUT Status		Good condition
Adapter Information		N/A

Objective

The objective of the manufacturer is to demonstrate compliance with Certification Ordinance Article 2-1-19, rules and limits for this device including:

- Frequency Error
- Occupied Bandwidth
- Transmitter Spurious Emission and Unwanted Emission Intensity
- Antenna Output Power And Output Power Tolerance
- Receiver Spurious Emission Strength
- Interference Prevention Function
- Construction Protection Confirmation

Test Method

MIC Notice No.88 Appendix No.43

Measurement Uncertainty

Item	Expanded Measurement uncertainty
Frequency error	56.6Hz(k=2, 95% level of confidence)
Occupied Channel Bandwidth	109.2kHz(k=2, 95% level of confidence)
RF output power, conducted	0.86dB(k=2, 95% level of confidence)
Unwanted Emission, conducted	1.60dB(k=2, 95% level of confidence)
Duty Cycle	±1%
Temperature	±1°C
Supply voltages	±0.4%
Humidity	±1%

Note: The extended uncertainty given in this report is obtained by combining the standard uncertainty times the coverage factor K with the 95% confidence interval. Otherwise required by the applicant or Product Regulations, Decision Rule in this report did not consider the uncertainty.

Test Facility

The Test site used by Bay Area Compliance Laboratories Corp. (Shenzhen) to collect test data is located on the 5F(B-West) , 6F, 7F, the 3rd Phase of Wan Li Industrial Building D, Shihua Rd, FuTian Free Trade Zone, Shenzhen, China.

Each test item follows test standards and with no deviation.

EUT TEST CONFIGURATION

Description of Test Configuration

The system was configured for testing in a testing mode by some software.

For BLE 1M mode, 40 channels are provided for testing:

Channel	Frequency(MHz)	Channel	Frequency(MHz)
0	2402	20	2442
1	2404	21	2444
...	...	...	...
...	...	...	...
...	...	...	...
18	2438	38	2478
19	2440	39	2480

EUT was tested with channel 0, 19 and 39.

For BLE 2M mode, 40 channels are provided for testing:

Channel	Frequency(MHz)	Channel	Frequency(MHz)
0	2402	20	2442
1	2404	21	2444
...	...	...	...
...	...	...	...
...	...	...	...
18	2438	38	2478
19	2440	39	2480

EUT was tested with channel 0, 19 and 39.

Normal/Extreme Voltage Condition[#]

NV	Normal Voltage	3.6V
LV	Low Voltage	3.24V
HV	High Voltage	3.96V

Note: extreme voltage test conditions were declared by manufacturer.

EUT Exercise Software

Exercise Software#	nRF_DTM.exe		
Power Level#			
Mode	Low Channel	Middle Channel	High Channel
BLE 1M	4DBM	4 DBM	4 DBM
BLE 2M	4 DBM	4DBM	4 DBM

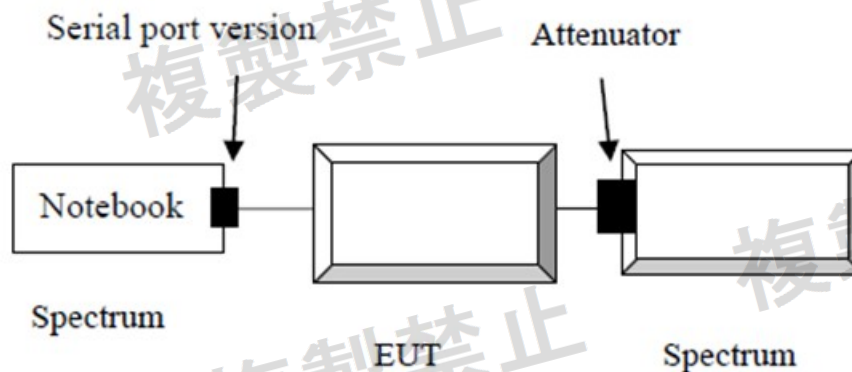
Equipment Modifications

No modification was made to the EUT tested.

Support Equipment List and Details

Manufacturer	Description	Model	Serial Number
DELL	Notebook	Latitude E6410	11429208685
Unknown	Serial port version	Unknown	Unknown

Cable Description	Length(m)	From/Port	To
Unshielded Un-Detachable Cable	0.2	Serial port version	EUT

Configuration of Test Setup

SUMMARY OF TEST RESULTS

MIC Notice No.88 Appendix No.43 Article 2, Paragraph 1, Item 19	Description of Test	Result
1	Frequency Error	Compliant
2	Occupied Bandwidth	Compliant
3	Transmitter Spurious Emission and Unwanted Emission Intensity	Compliant
4	Antenna Output Power and Output Power Tolerance	Compliant
5	Receiver Spurious Emission and Unwanted Emission Intensity	Compliant
6	Transmission Antenna Gain	Not Applicable
7	Carrier sense capability	Not Applicable**
8	Transmission Radiation Angle Width	Not Applicable
9	Frequency Hopping Dwell Time	Not Applicable*
10	Interference Prevention Function	Compliant
11	Construction Protection Confirmation	Compliant

Not Applicable* -Testing is only required for FHSS system devices.

Not Applicable**-The OBW of EUT is less than 26 MHz.

Not Applicable - This test item was not required for the output power less than 12.14 dBm (E.I.R.P)

TEST EQUIPMENT LIST

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Authority	Calibration Method
Rohde & Schwarz	Spectrum Analyzer	FSV40	101942	2025/09/01	2026/08/31	CCIC	c)
Unknown	10dB Attenuator	Unknown	F-03-EM190	2025/06/26	2026/06/25	BACL	d)
Rohde & Schwarz	Wideband Radio Communication Tester	CMW500	141718	2025/07/18	2026/07/17	BACL Cal	c)
Tonscend	RF control Unit	JS0806-2	19D8060154	2025/07/18	2026/07/17	BACL Cal	c)

Note: Calibration Method

a) Calibration conducted by the National Institute of Information and Communications Technology (NICT) or a designated calibration agency under Article 102-18 paragraph (1)

b) Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992) ~Japan Calibration Service System~

c) Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1)

d) Calibration conducted by using other equipment that listed above from a) to c)

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

REQUIREMENTS AND TEST PROCEDURES

Frequency Error

Limit

50 ppm or below

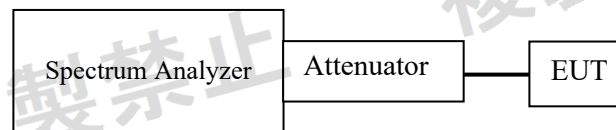
Test Procedure

Set the EUT to the measurement frequency without modulation.
Setting of SA is following as:

- Center Frequency: Frequency to measure
- RBW: 1 kHz, VBW: 3 kHz
- Span: 300KHz
- Sweep time: Auto
- Log scale: 10dB/Div, Data points: 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak
- Sweep mode: Single Sweep
- Marker: Spot

Record the peak spot frequency.

If the EUT can't set at un-modulation mode, measure the 10dBc center frequency.



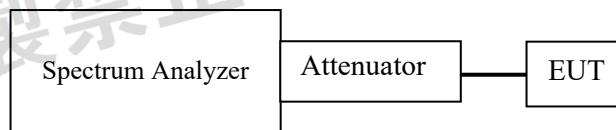
Occupied Bandwidth

Limit

- Occupied bandwidth: FH $\leq$ 83.5 MHz; OFDM, DS $\leq$ 26 MHz; Others $\leq$ 26 MHz

Test Procedure

1. Setting of SA is following as:
 - Center Frequency: Frequency to measure
 - RBW: 30 kHz, VBW: 30 kHz
 - Sweep time: Auto
 - Log scale: 10dB/Div, Data points: 400 points or more
 - Reference level: Enough level for maximum dynamic range
 - Detection: Positive Peak
 - Sweep mode: Continuous Sweep
 - Marker: Spot
2. EUT have transmitted the maximum modulation signal and fixed channelize. SA set to 99% of occupied bandwidth to measure occupied bandwidth.



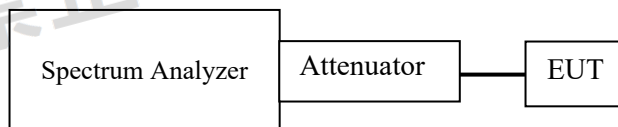
Transmitter Spurious Emission Strength and Unwanted Emission Intensity

Limit

- $f < 2387 \text{ MHz}$, $f > 2496.5 \text{ MHz}$: $\leq 2.5 \mu\text{W/MHz}$
- $2387 \text{ MHz} \leq f \leq 2400 \text{ MHz}$; $2483.5 \text{ MHz} < f \leq 2496.5 \text{ MHz}$: $\leq 25 \mu\text{W/MHz}$

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be in continuously transmitting mode.

Spectrum Analyzer Conditions

- Span: Measuring Frequency Range
- RBW: 1MHz (frequency range; 1GHz over), 100kHz (frequency range; 30MHz to 1GHz)
- VBW: Same as RBW (1MHz or 100kHz)
- Sweep time: Auto (Minimum time to ensure measurement accuracy.)
- Data points : 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak

If the measured value is under the technical standard value, do not need to measure more detail.

Note: $2.5 \mu\text{W/MHz} = 0.25 \mu\text{W}/100\text{kHz}$

Antenna Output Power and Antenna Power Tolerance

Limit

Antenna power:

- ≤ 10 mW/MHz (OFDM, DSSS from 2400-2483.5 MHz)
- ≤ 10 mW (other from 2400-2483.5 MHz)

The Output Power Tolerance must be within +20%, -80%.

E.i.r.p:

- ≤ 12.14 dBm/MHz (OFDM (20MHz system), DSSS form 2400-2483.5MHz)
- ≤ 9.13 dBm/MHz (OFDM(40MHz system) from 2400-2483.5MHz)
- ≤ 12.14 dBm (other from 2400-2483.5MHz)

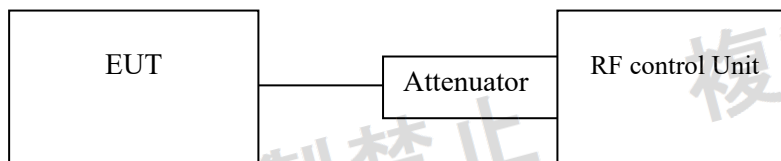
Test Procedure

Step 1: Measure the total power by Power Meter.

Step 2: If it's the burst wave, set the power meter to measure averaging across the burst transmit on period.

Step 3: Record the reading on power meter as antenna output power.

Test Setup Block diagram



Note: the power meter was integrated in the RF control Unit.

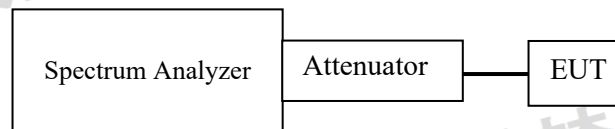
Receiver Spurious Emission and Unwanted Emission Intensity

Limit

- $\leq 4\text{nW}$ ($30\text{ MHz} \leq f \leq 1000\text{ MHz}$)
- $\leq 20\text{ nW}$ ($f \geq 1\text{ GHz}$)

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be “continuous receiving mode”.

Spectrum Analyzer Conditions

- Start Frequency: Start Frequency of frequency range to measure (30MHz or 1GHz)
- Stop Frequency: Stop Frequency of frequency range to measure (1GHz or 12.5GHz)
- Span: AUTO (Measurement Range)
- RBW: 100 kHz, VBW: 100 kHz for Frequency < 1 GHz
- RBW: 1MHz, VBW: 1MHz for Frequency > 1 GHz
- Sweep time: AUTO or more
- Sweep mode: Auto Sweep
- Detection: Positive Peak
- Reference Level: Enough level for maximum dynamic range

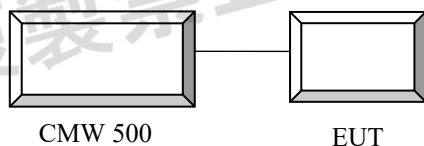
Interference Prevention Function

Requirement

The EUT shall have the interference prevention capability to transmit or to receive the identification automatically, so that sender and receiver shall exclude other equipment.

Test Procedure

Measurement System Diagram



In the case that the EUT has the function of automatically transmitting the identification code:

1. Transmit the predetermined identification codes from EUT
2. Check the transmitted identification codes with the demodulator.

In the case of receiving the identification codes:

1. Transmit the predetermined identification codes from the counterpart.
2. Check if communication is normal
3. Transmit the signal other than predetermined ID codes from the counterpart.
4. Check if the EUT stops the transmission, or if it displays that identification codes are different from the predetermined ones.

TEST DATA AND RESULTS**Frequency Error****Test Information:**

Sample No.:	3BRX-2	Test Date:	2025/11/10
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	26.2	Relative Humidity: (%)	53	ATM Pressure: (kPa)	100.7
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Test Condition: NV

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.99625	-1.56	± 50	Pass
	2440	2439.99625	-1.54		Pass
	2480	2479.99625	-1.51		Pass

Test Condition: LV

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.99625	-1.56	± 50	Pass
	2440	2439.99625	-1.54		Pass
	2480	2479.99595	-1.63		Pass

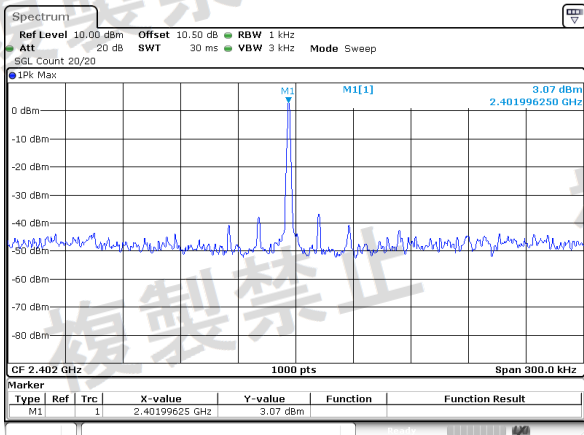
Test Condition: HV

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.99625	-1.56	± 50	Pass
	2440	2439.99625	-1.54		Pass
	2480	2479.99595	-1.63		Pass

Frequency Tolerance = (Measure Frequency - Frequency)/Frequency*10⁶

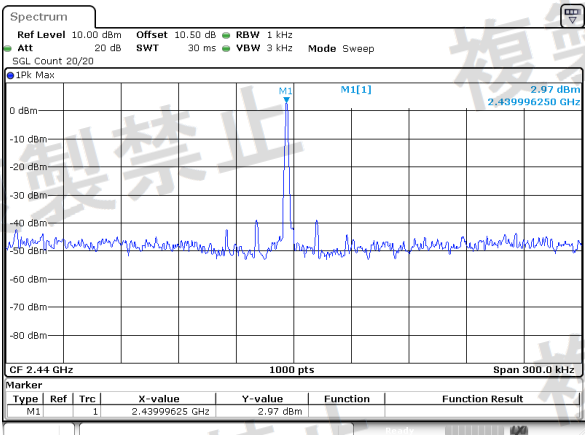
Test Condition: NV

2402MHz



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:58:06

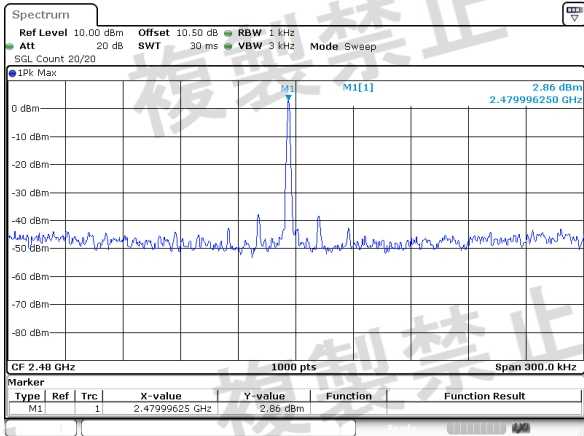
2440MHz



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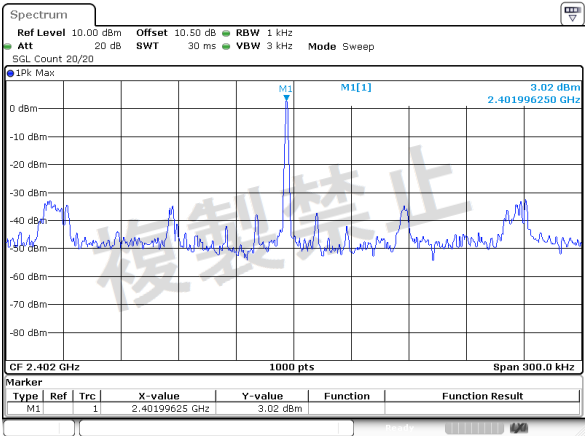
Test Condition: LV

2480MHz



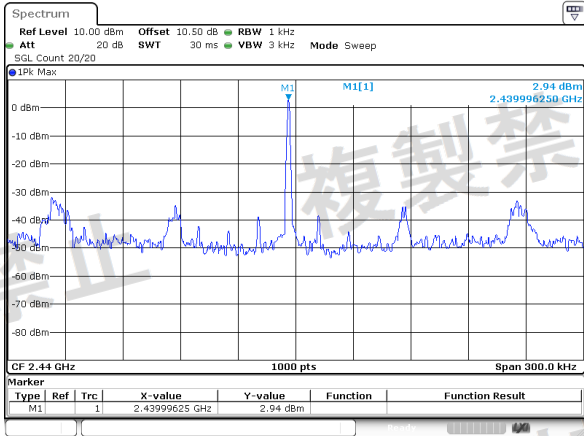
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2402MHz



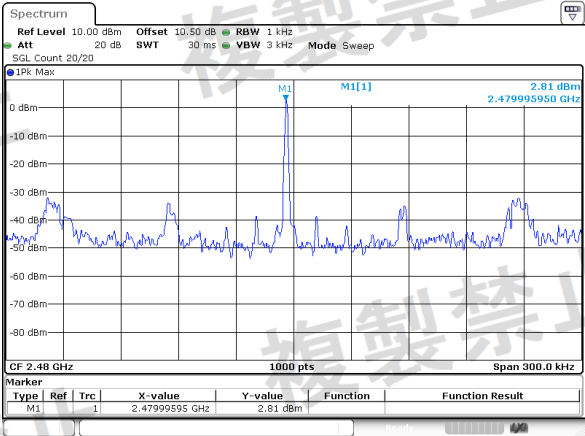
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2440MHz



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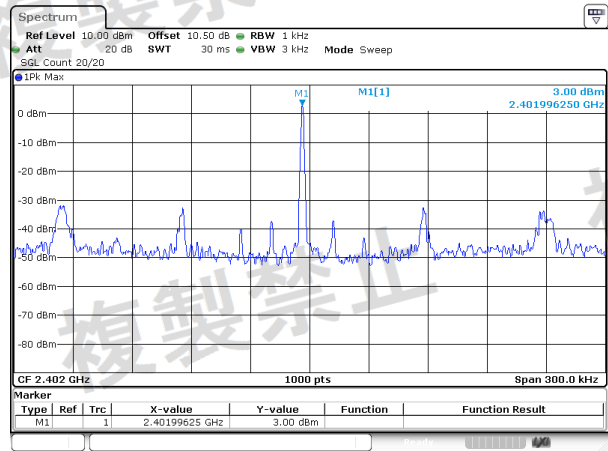
2480MHz



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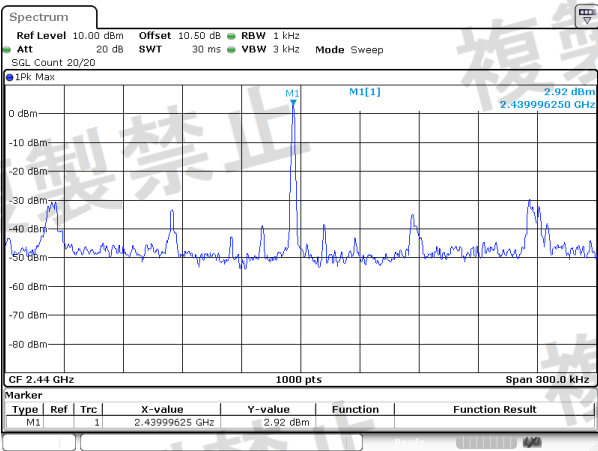
Test Condition: HV

2402MHz



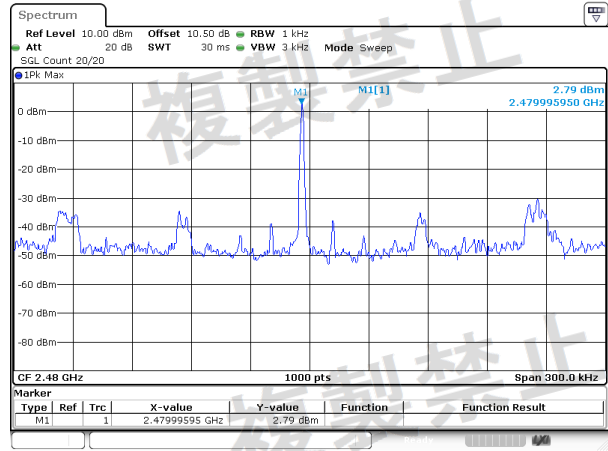
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2440MHz



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:42:56

2480MHz



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:44:34

Occupied Bandwidth**Test Information:**

Sample No.:	3BRX-2	Test Date:	2025/11/10
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	26.2	Relative Humidity: (%)	53	ATM Pressure: (kPa)	100.7
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Test Condition: NV

Mode	Occupied bandwidth (MHz)			Limit(MHz)	Verdict
	Low Channel	Middle Channel	High Channel		
BLE 1M	1.048	1.048	1.05	≤ 26	Pass
BLE 2M	2.05	2.055	2.065		Pass

Test Condition: LV

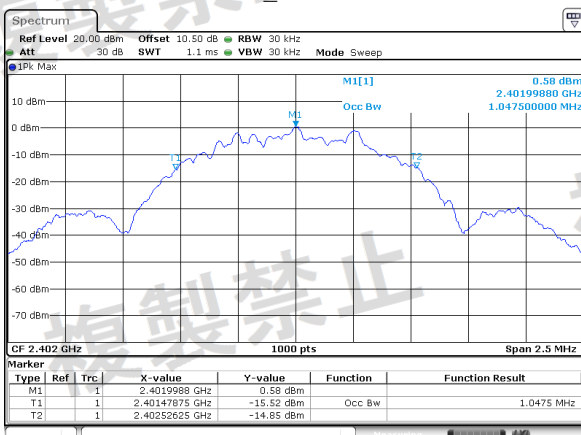
Mode	Occupied bandwidth (MHz)			Limit(MHz)	Verdict
	Low Channel	Middle Channel	High Channel		
BLE 1M	1.050	1.053	1.055	≤ 26	Pass
BLE 2M	2.05	2.055	2.06		Pass

Test Condition: HV

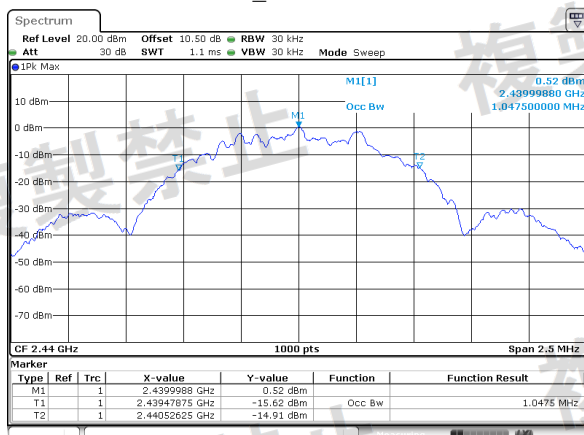
Mode	Occupied bandwidth (MHz)			Limit(MHz)	Verdict
	Low Channel	Middle Channel	High Channel		
BLE 1M	1.05	1.05	1.053	≤ 26	Pass
BLE 2M	2.05	2.055	2.060		Pass

Test Condition: NV

BLE 1M_Low Channel

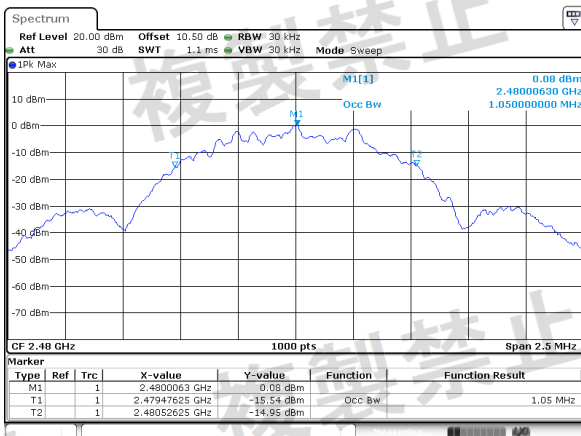


BLE 1M_Middle Channel

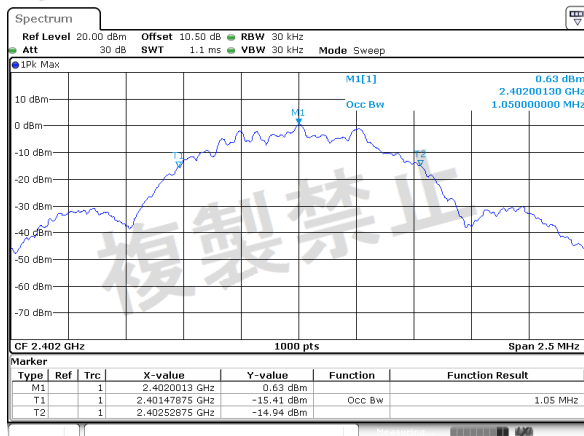


Test Condition: LV

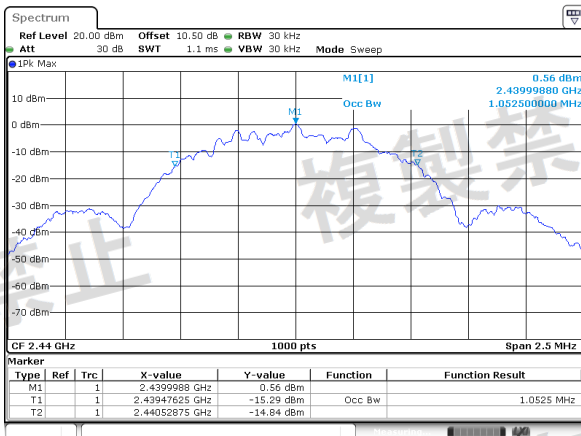
BLE 1M_High Channel



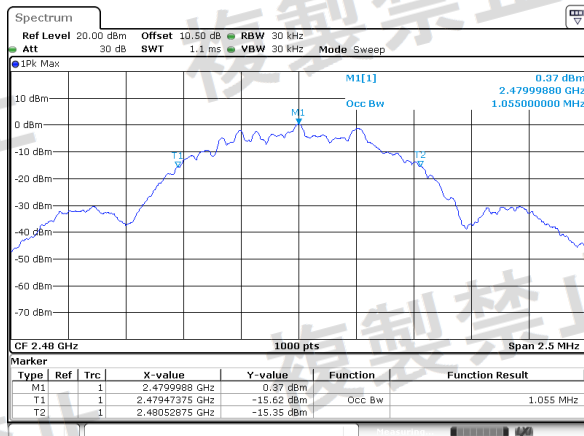
BLE 1M_Low Channel



BLE 1M_Middle Channel

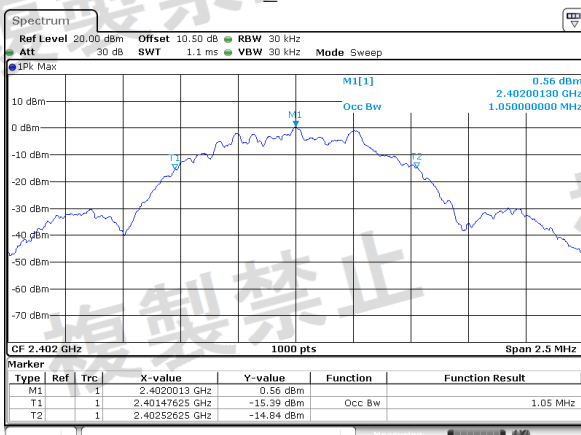


BLE 1M_High Channel

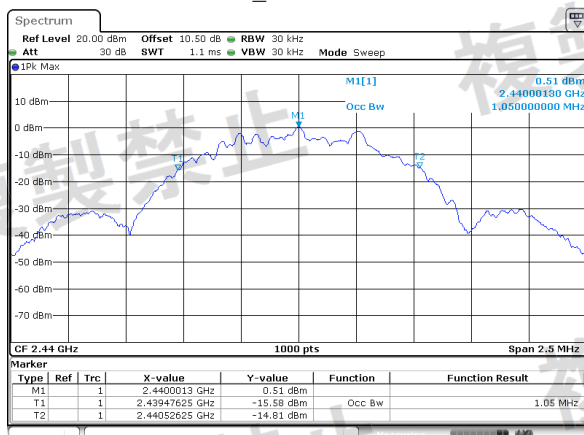


Test Condition: HV

BLE 1M_Low Channel

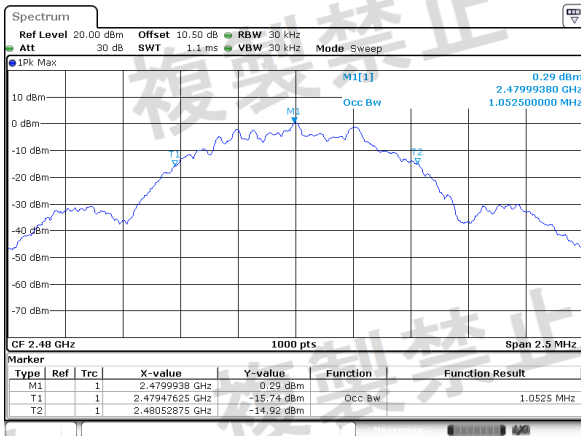


BLE 1M_Middle Channel

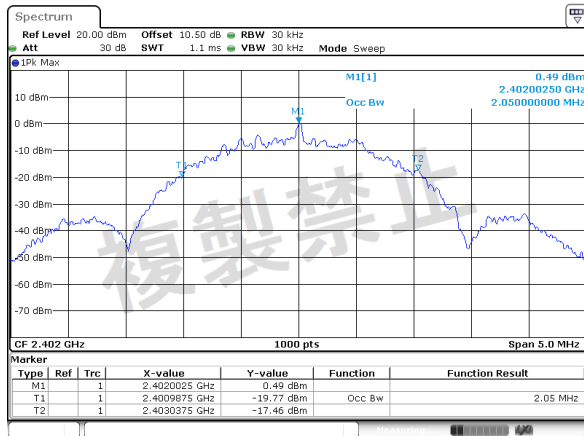


Test Condition: NV

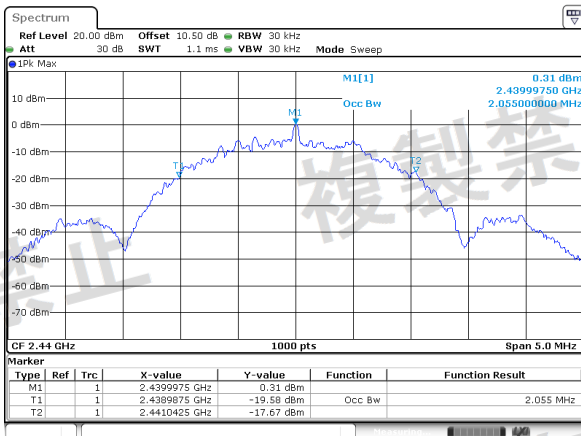
BLE 1M_High Channel



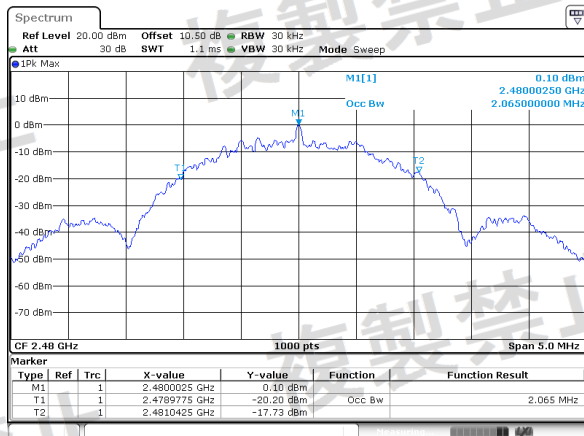
BLE 2M_Low Channel



BLE 2M_Middle Channel

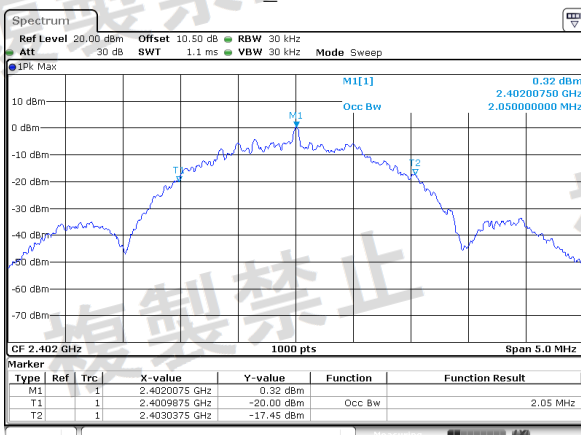


BLE 2M_High Channel



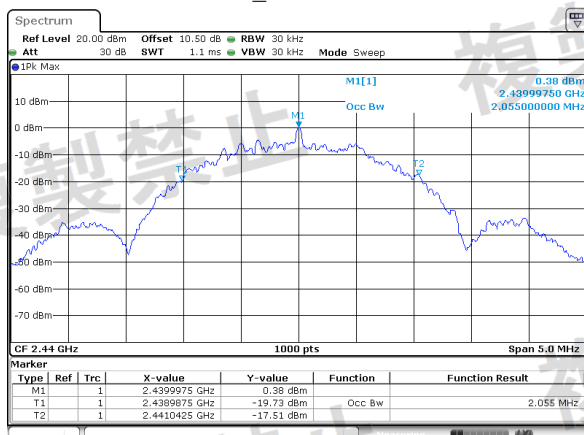
Test Condition: LV

BLE 2M_Low Channel



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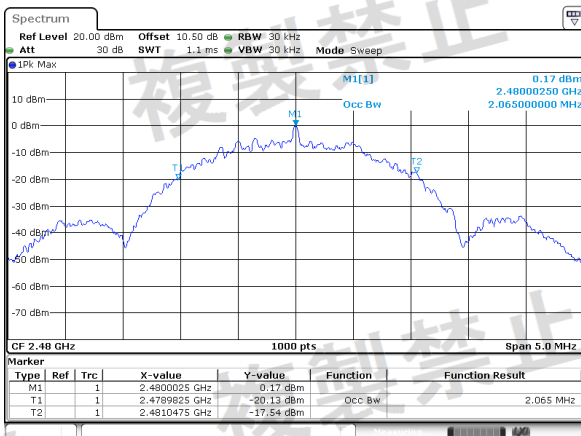
BLE 2M_Middle Channel



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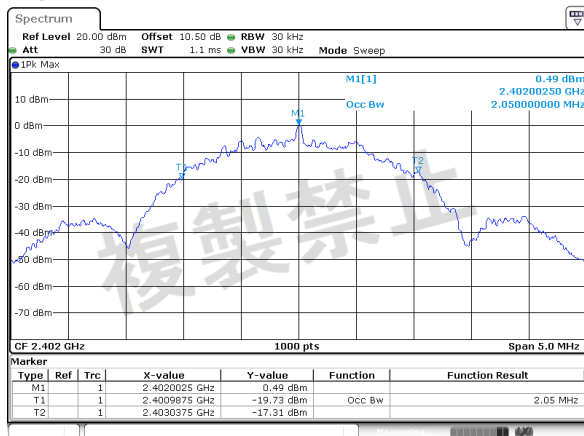
Test Condition: HV

BLE 2M_High Channel



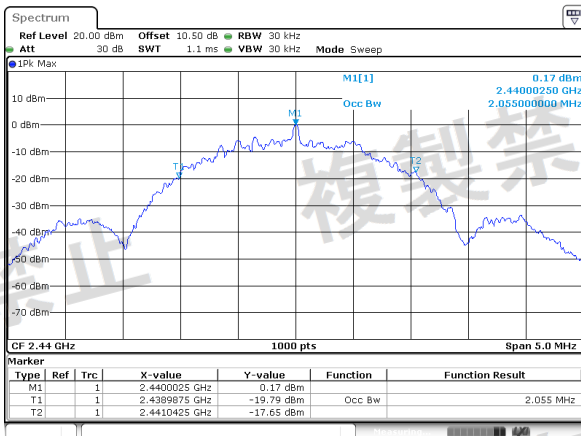
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BLE 2M_Low Channel



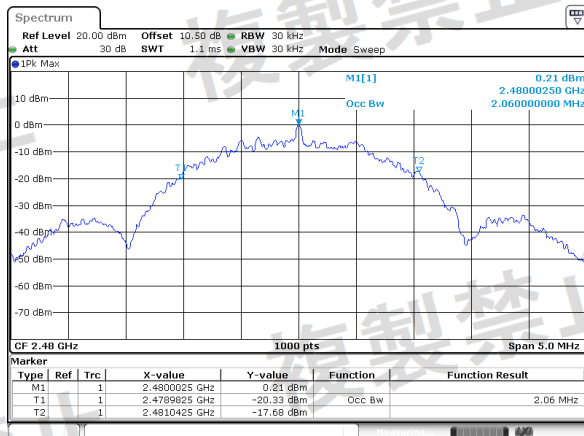
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:54:05

BLE 2M_Middle Channel



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:56:49

BLE 2M_High Channel



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:59:15

Transmitter Spurious Emission and Unwanted Emission Intensity**Test Information:**

Sample No.:	3BRX-2	Test Date:	2025/11/10
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	26.2	Relative Humidity: (%)	53	ATM Pressure: (kPa)	100.7
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Test Condition: Normal, BLE 1M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	987.63	-47.11	0.019	0.25	Pass
	Band II (1MHz)	1000	2387	2010.78	-38.47	0.142	2.50	Pass
	Band III (1MHz)	2387	2400	2399.5223	-28.89	1.291	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2488.6773	-37.75	0.168	25	Pass
	Band V (1MHz)	2496.5	12500	6815.5	-33.46	0.451	2.50	Pass
Middle	Band I (100kHz)	30	1000	959.02	-46.68	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	1625.88	-36.88	0.205	2.50	Pass
	Band III (1MHz)	2387	2400	2387.4258	-37.88	0.163	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2485.5508	-36.87	0.206	25	Pass
	Band V (1MHz)	2496.5	12500	6510.4	-32.83	0.521	2.50	Pass
High	Band I (100kHz)	30	1000	957.56	-46.80	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	1782.61	-38.38	0.145	2.50	Pass
	Band III (1MHz)	2387	2400	2387.9328	-38.61	0.138	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.6918	-31.06	0.783	25	Pass
	Band V (1MHz)	2496.5	12500	6900.5	-32.91	0.512	2.50	Pass

Test Condition: Normal, BLE 2M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	867.35	-46.27	0.024	0.25	Pass
	Band II (1MHz)	1000	2387	1653.62	-37.89	0.163	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9968	-18.30	14.791	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2485.0633	-38.17	0.152	25	Pass
	Band V (1MHz)	2496.5	12500	5835.2	-33.42	0.455	2.50	Pass
Middle	Band I (100kHz)	30	1000	862.99	-47.41	0.018	0.25	Pass
	Band II (1MHz)	1000	2387	1770.13	-37.63	0.173	2.50	Pass
	Band III (1MHz)	2387	2400	2388.1538	-38.71	0.135	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2494.6313	-38.61	0.138	25	Pass
	Band V (1MHz)	2496.5	12500	6860.5	-32.47	0.566	2.50	Pass
High	Band I (100kHz)	30	1000	941.56	-45.86	0.026	0.25	Pass
	Band II (1MHz)	1000	2387	1444.88	-37.87	0.163	2.50	Pass
	Band III (1MHz)	2387	2400	2392.6128	-38.24	0.150	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.7438	-31.00	0.794	25	Pass
	Band V (1MHz)	2496.5	12500	6715.5	-32.44	0.570	2.50	Pass

Test Condition: LV, BLE 1M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	235.88	-47.22	0.019	0.25	Pass
	Band II (1MHz)	1000	2387	1710.49	-38.52	0.141	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9968	-29.30	1.175	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2496.1133	-37.46	0.179	25	Pass
	Band V (1MHz)	2496.5	12500	5835.2	-32.65	0.543	2.50	Pass
Middle	Band I (100kHz)	30	1000	964.84	-47.23	0.019	0.25	Pass
	Band II (1MHz)	1000	2387	1394.25	-37.58	0.175	2.50	Pass
	Band III (1MHz)	2387	2400	2394.2183	-38.01	0.158	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.5303	-38.43	0.144	25	Pass
	Band V (1MHz)	2496.5	12500	6640.4	-33.31	0.467	2.50	Pass
High	Band I (100kHz)	30	1000	204.36	-46.51	0.022	0.25	Pass
	Band II (1MHz)	1000	2387	1416.45	-38.13	0.154	2.50	Pass
	Band III (1MHz)	2387	2400	2395.5768	-37.66	0.171	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.9973	-31.14	0.769	25	Pass
	Band V (1MHz)	2496.5	12500	6925.5	-32.84	0.520	2.50	Pass

Test Condition: LV, BLE 2M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	955.62	-47.30	0.019	0.25	Pass
	Band II (1MHz)	1000	2387	1696.62	-37.78	0.167	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9903	-18.31	14.757	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2486.6493	-37.92	0.161	25	Pass
	Band V (1MHz)	2496.5	12500	6950.6	-33.21	0.478	2.50	Pass
Middle	Band I (100kHz)	30	1000	483.72	-46.73	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	1585.66	-38.61	0.138	2.50	Pass
	Band III (1MHz)	2387	2400	2392.8858	-37.92	0.161	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2496.4318	-38.44	0.143	25	Pass
	Band V (1MHz)	2496.5	12500	6260.3	-32.87	0.516	2.50	Pass
High	Band I (100kHz)	30	1000	737.37	-46.73	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	1739.62	-37.84	0.164	2.50	Pass
	Band III (1MHz)	2387	2400	2392.0733	-38.54	0.140	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.7958	-31.44	0.718	25	Pass
	Band V (1MHz)	2496.5	12500	6895.5	-33.13	0.486	2.50	Pass

Test Condition: HV, BLE 1M

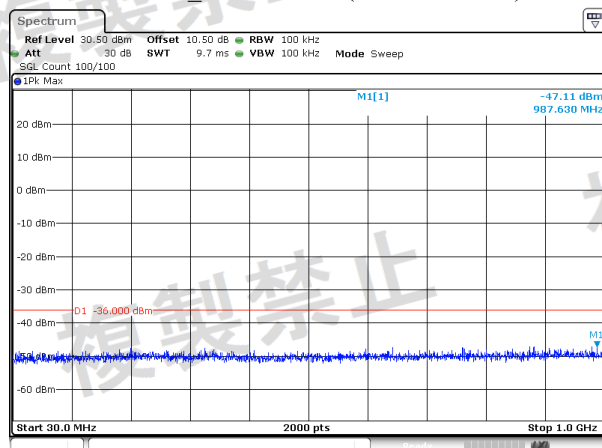
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	939.13	-46.59	0.022	0.25	Pass
	Band II (1MHz)	1000	2387	1756.96	-37.67	0.171	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9968	-29.24	1.191	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2491.6738	-38.31	0.148	25	Pass
	Band V (1MHz)	2496.5	12500	6945.6	-33.05	0.495	2.50	Pass
Middle	Band I (100kHz)	30	1000	987.63	-46.46	0.023	0.25	Pass
	Band II (1MHz)	1000	2387	1778.45	-38.10	0.155	2.50	Pass
	Band III (1MHz)	2387	2400	2389.5318	-38.44	0.143	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2488.1703	-38.11	0.155	25	Pass
	Band V (1MHz)	2496.5	12500	9386.4	-33.02	0.499	2.50	Pass
High	Band I (100kHz)	30	1000	997.82	-46.90	0.020	0.25	Pass
	Band II (1MHz)	1000	2387	1653.62	-38.10	0.155	2.50	Pass
	Band III (1MHz)	2387	2400	2399.6653	-37.99	0.159	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.4328	-31.36	0.731	25	Pass
	Band V (1MHz)	2496.5	12500	6875.5	-32.98	0.504	2.50	Pass

Test Condition: HV, BLE 2M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	355.19	-47.06	0.020	0.25	Pass
	Band II (1MHz)	1000	2387	1691.07	-38.16	0.153	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9968	-18.16	15.276	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2486.4218	-38.53	0.140	25	Pass
	Band V (1MHz)	2496.5	12500	6755.5	-33.03	0.498	2.50	Pass
Middle	Band I (100kHz)	30	1000	695.66	-46.87	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	1286.07	-37.56	0.175	2.50	Pass
	Band III (1MHz)	2387	2400	2396.5518	-38.98	0.126	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2493.3443	-37.81	0.166	25	Pass
	Band V (1MHz)	2496.5	12500	6810.5	-33.00	0.501	2.50	Pass
High	Band I (100kHz)	30	1000	305.24	-47.29	0.019	0.25	Pass
	Band II (1MHz)	1000	2387	2146.7	-37.66	0.171	2.50	Pass
	Band III (1MHz)	2387	2400	2395.8303	-38.02	0.158	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.6983	-31.27	0.746	25	Pass
	Band V (1MHz)	2496.5	12500	6940.6	-32.36	0.581	2.50	Pass

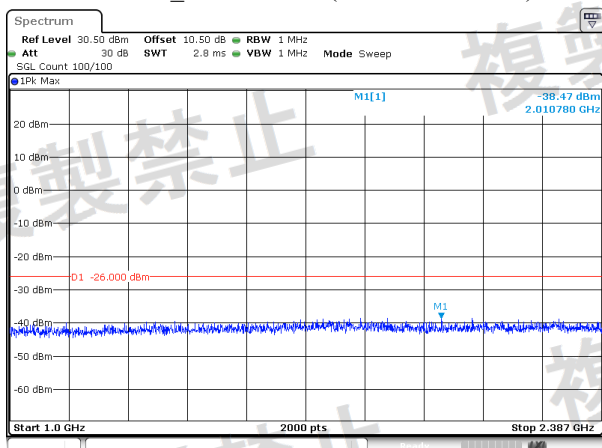
Test Condition: NV

BLE 1M_Low Channel(30MHz~1GHz)



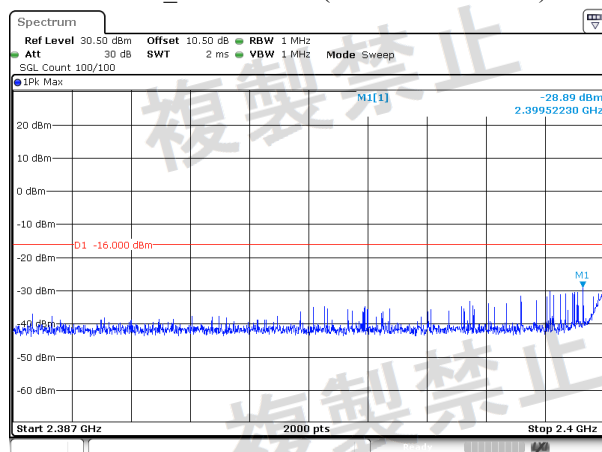
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:36:44

BLE 1M_Low Channel(1GHz~2.387GHz)



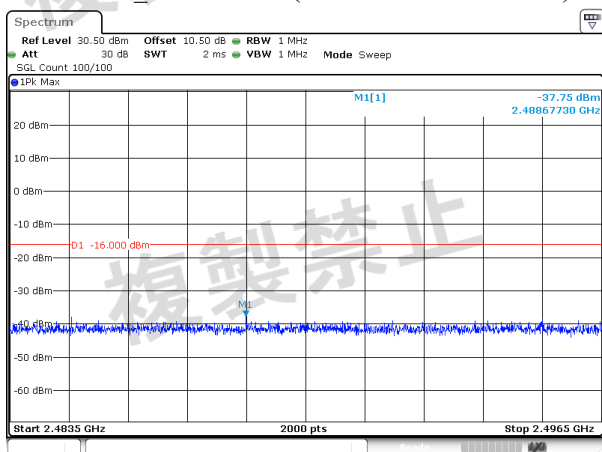
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Date: 10.NOV.2025 11:36:52

BLE 1M_Low Channel(2.387GHz~2.4GHz)



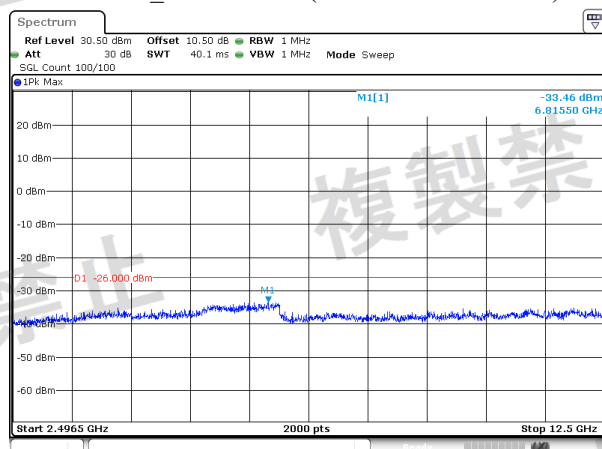
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Date: 10.NOV.2025 11:36:58

BLE 1M_Low Channel(2.4835GHz~2.4965GHz)



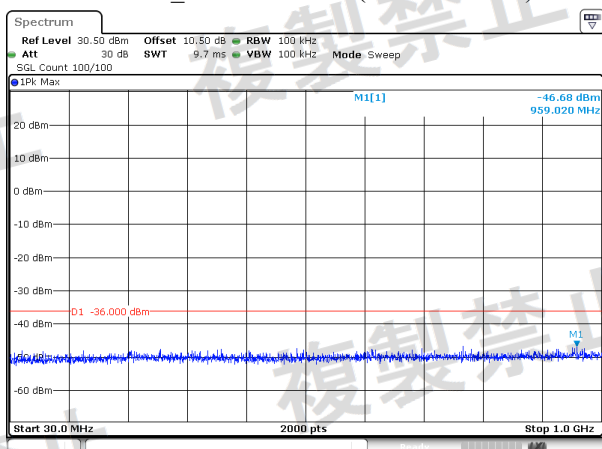
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Date: 10.NOV.2025 11:37:05

BLE 1M_Low Channel(2.4965GHz~12.5GHz)



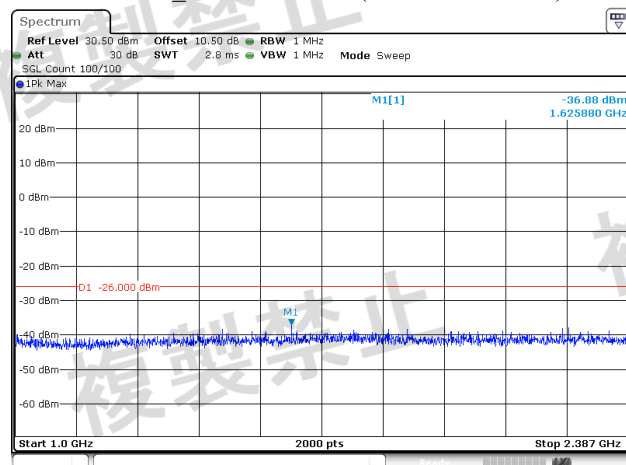
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Date: 10.NOV.2025 11:37:28

BLE 1M_Middle Channel(30MHz~1GHz)



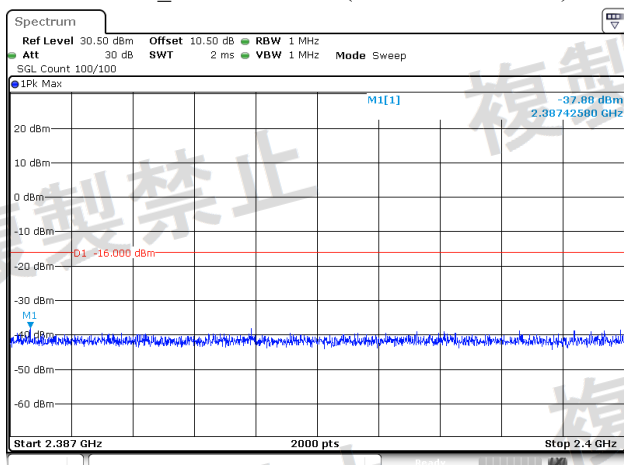
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:42:48

BLE 1M_Middle Channel(1GHz~2.387GHz)



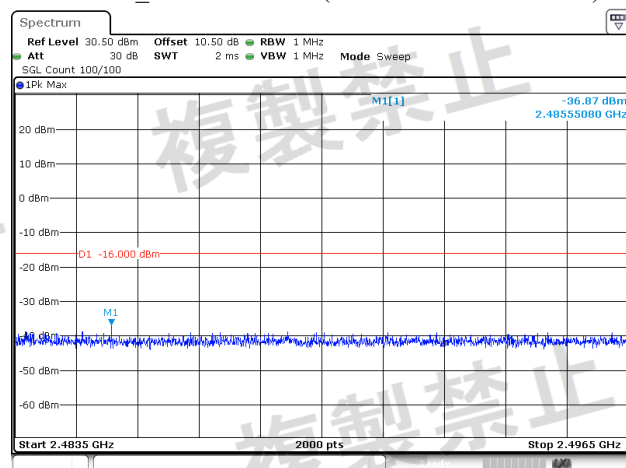
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Date: 10.NOV.2025 11:42:56

BLE 1M_Middle Channel(2.387GHz~2.4GHz)



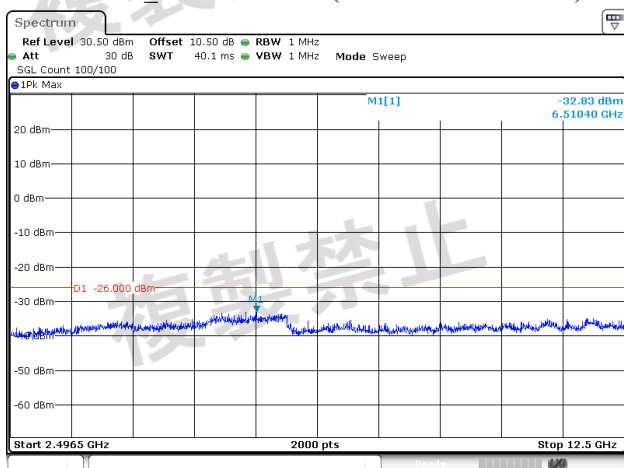
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BLE 1M_Middle Channel(2.4835GHz~2.4965GHz)



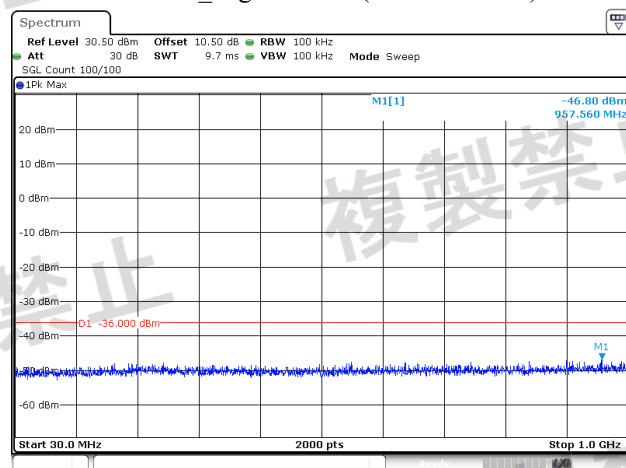
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BLE 1M_Middle Channel(2.4965GHz~12.5GHz)



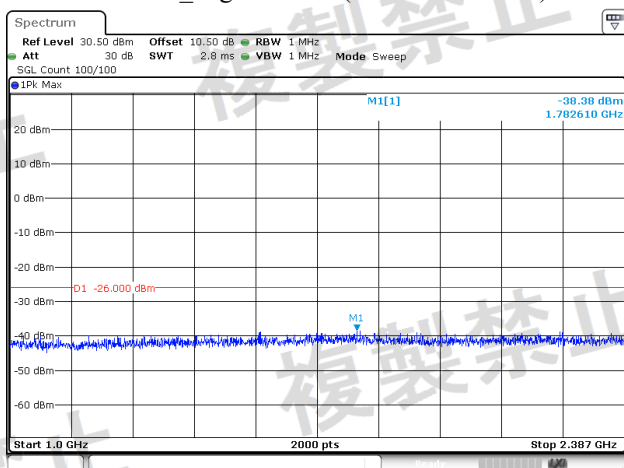
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Date: 10.NOV.2025 11:43:32

BLE 1M_High Channel(30MHz~1GHz)



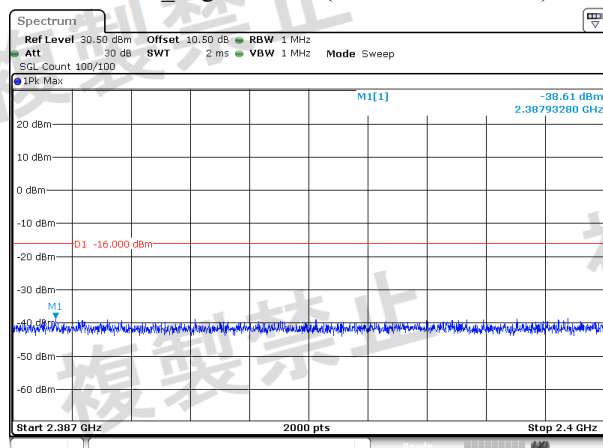
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Date: 10.NOV.2025 11:44:52

BLE 1M_High Channel(1GHz~2.387GHz)



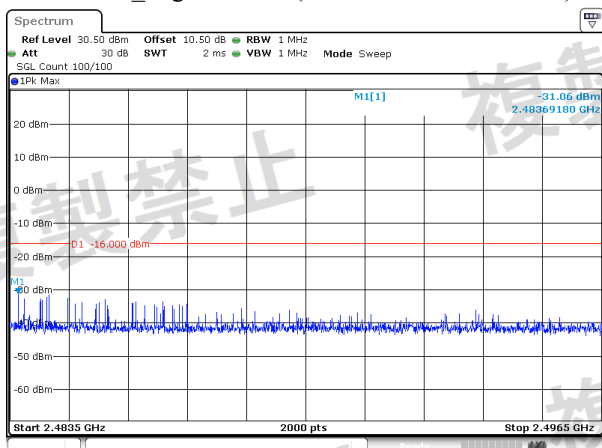
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Date: 10.NOV.2025 11:45:00

BLE 1M_High Channel(2.387GHz~2.4GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:45:07

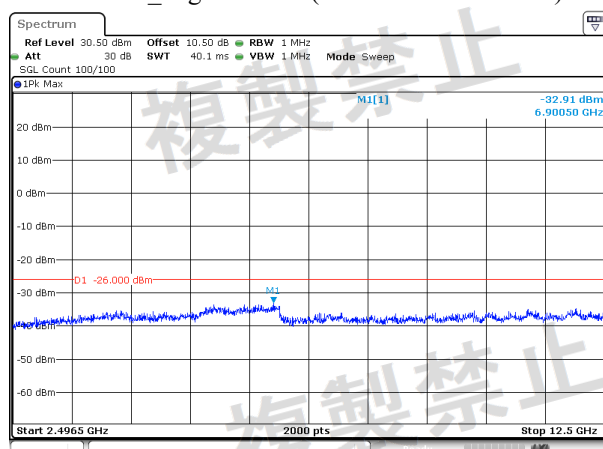
BLE 1M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:45:14

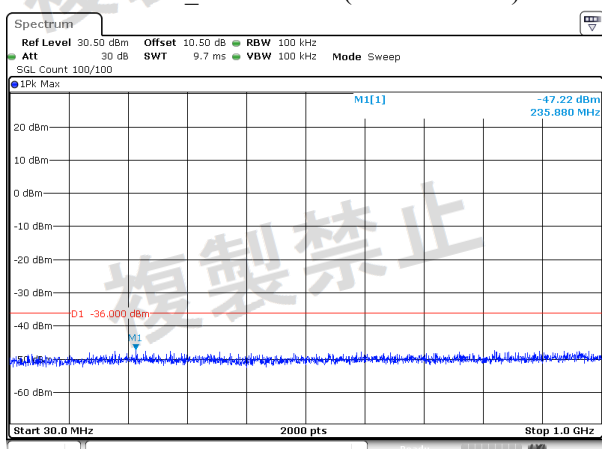
Test Condition: LV

BLE 1M_High Channel(2.4965GHz~12.5GHz)



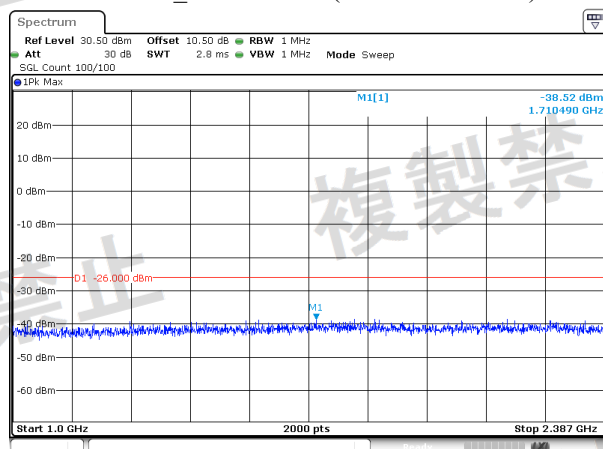
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Date: 10.NOV.2025 11:45:37

BLE 1M_Low Channel(30MHz~1GHz)



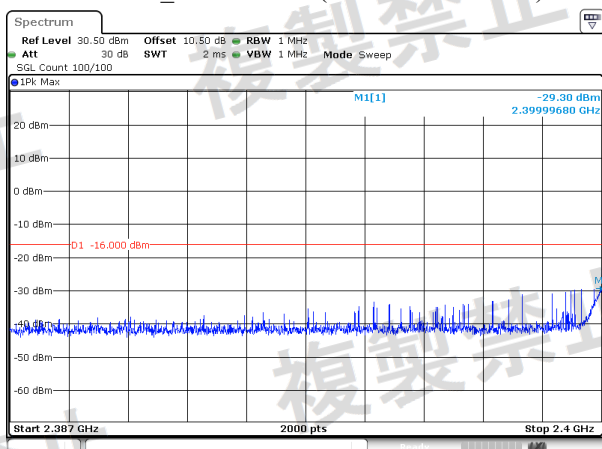
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BLE 1M_Low Channel(1GHz~2.387GHz)



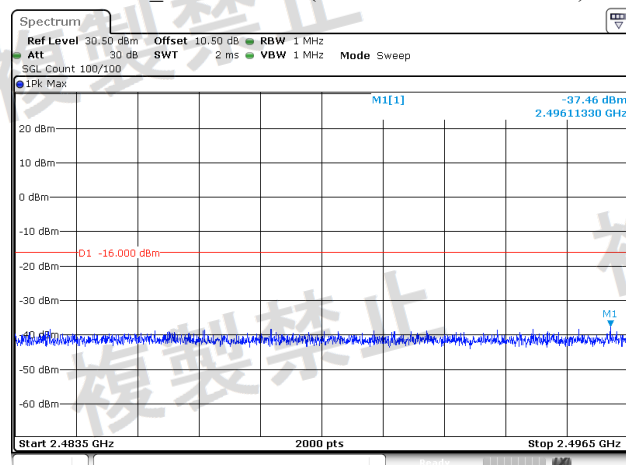
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BLE 1M_Low Channel(2.387GHz~2.4GHz)



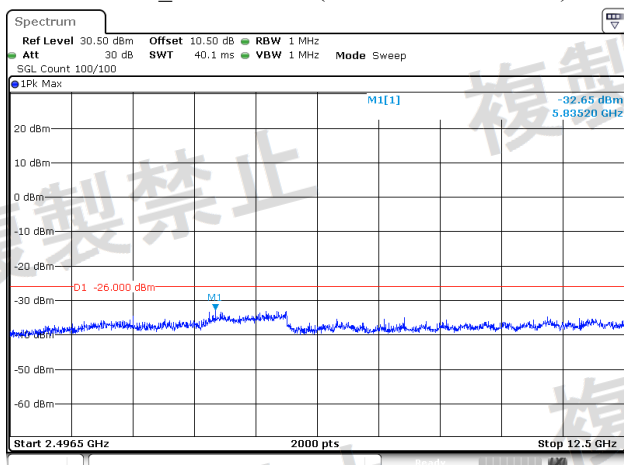
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BLE 1M_Low Channel(2.4835GHz~2.4965GHz)



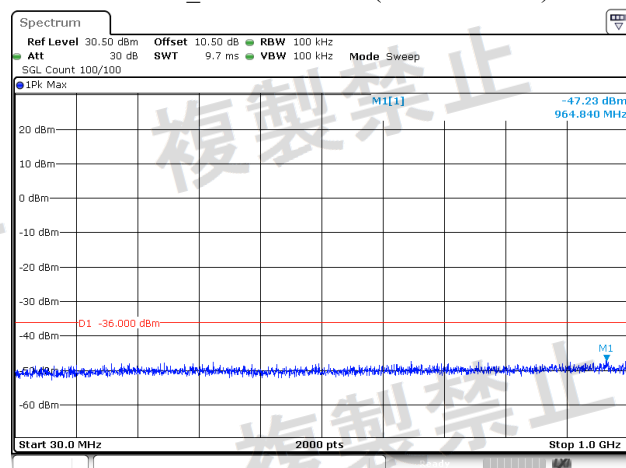
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BLE 1M_Low Channel(2.4965GHz~12.5GHz)



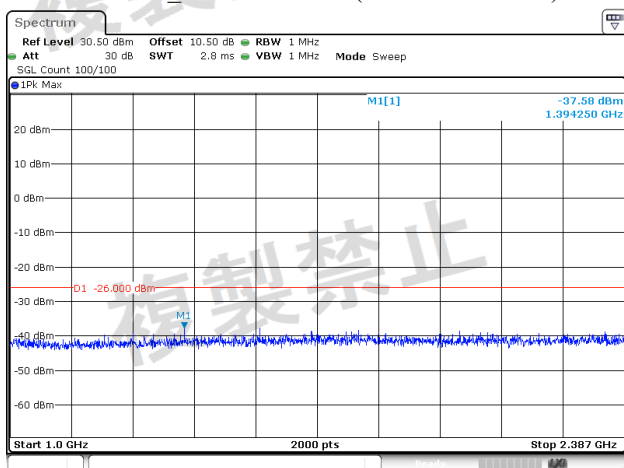
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BLE 1M_Middle Channel(30MHz~1GHz)



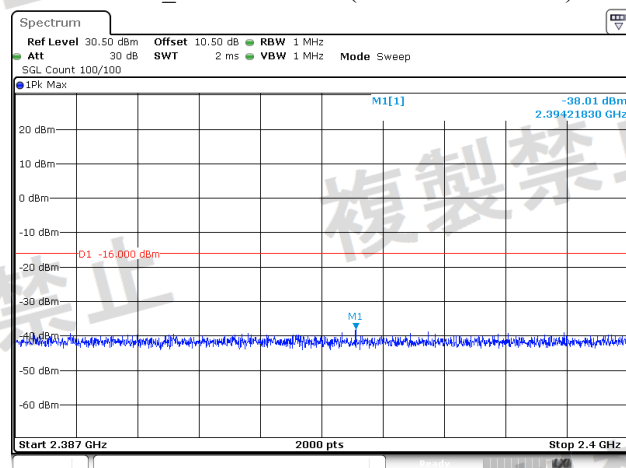
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BLE 1M_Middle Channel(1GHz~2.387GHz)



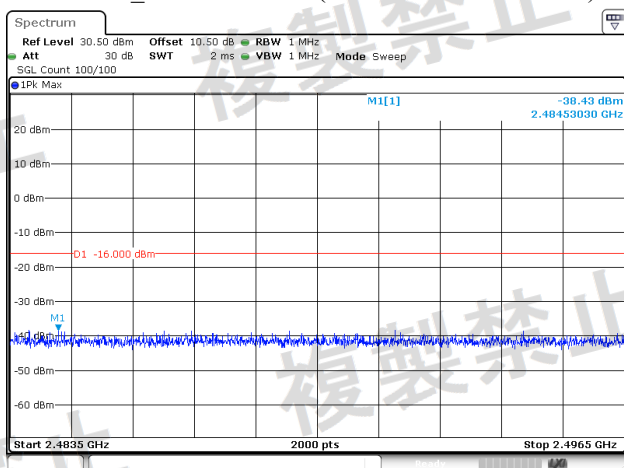
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BLE 1M_Middle Channel(2.387GHz~2.4GHz)



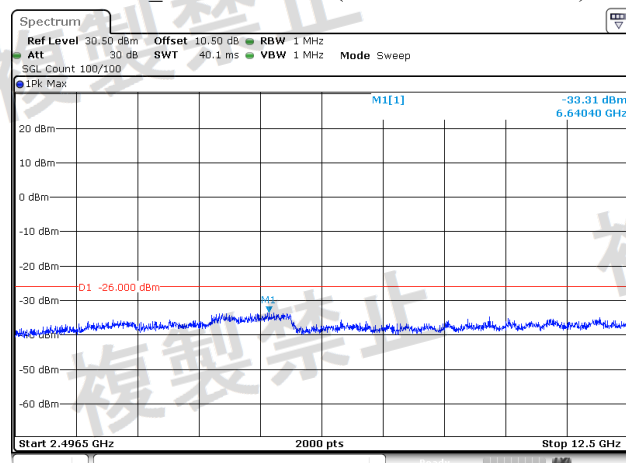
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:10:12

BLE 1M_Middle Channel(2.4835GHz~2.4965GHz)



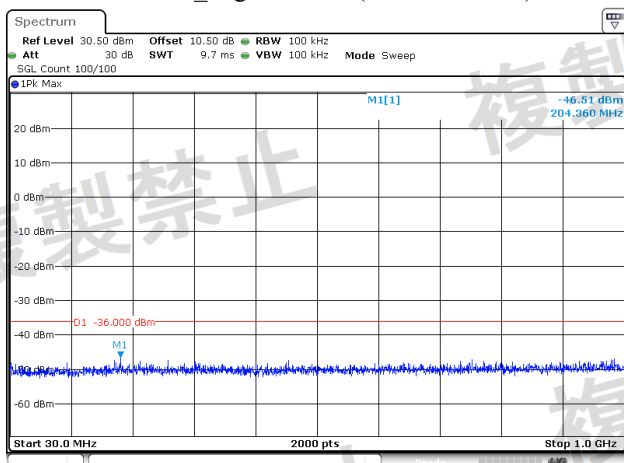
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:10:18

BLE 1M_Middle Channel(2.4965GHz~12.5GHz)



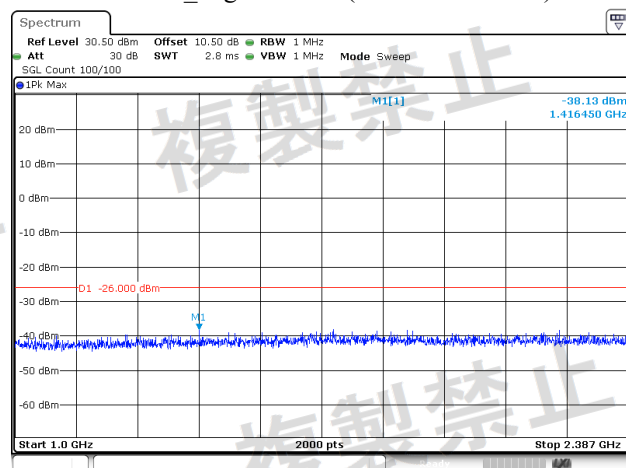
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:10:42

BLE 1M_High Channel(30MHz~1GHz)



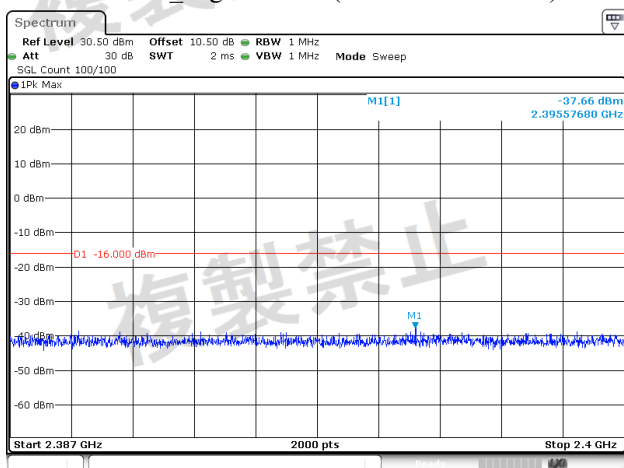
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:12:12

BLE 1M_High Channel(1GHz~2.387GHz)



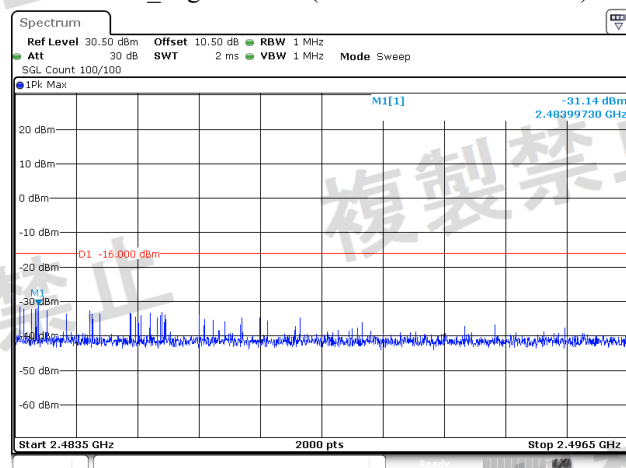
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:12:20

BLE 1M_High Channel(2.387GHz~2.4GHz)



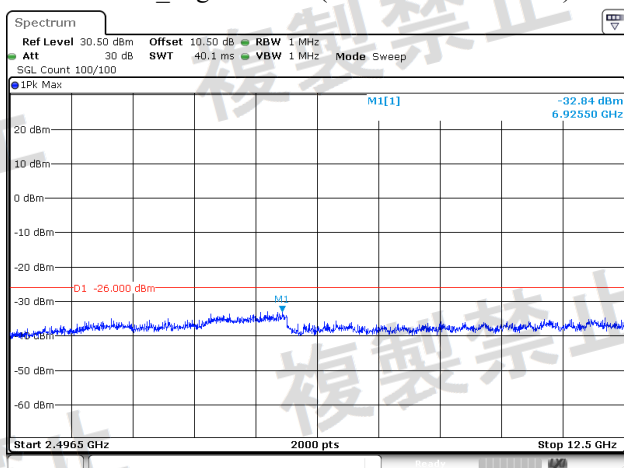
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:12:27

BLE 1M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:12:34

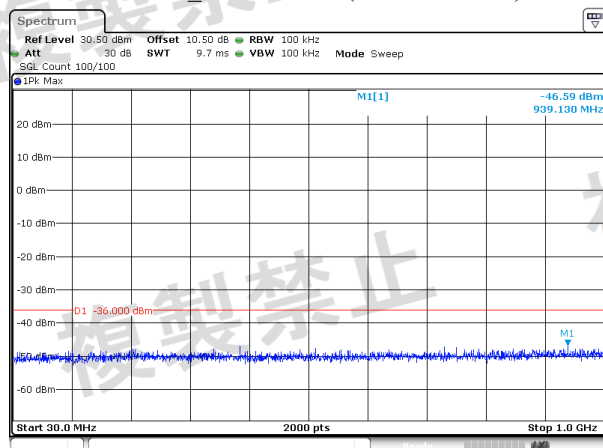
BLE 1M_High Channel(2.4965GHz~12.5GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:12:58

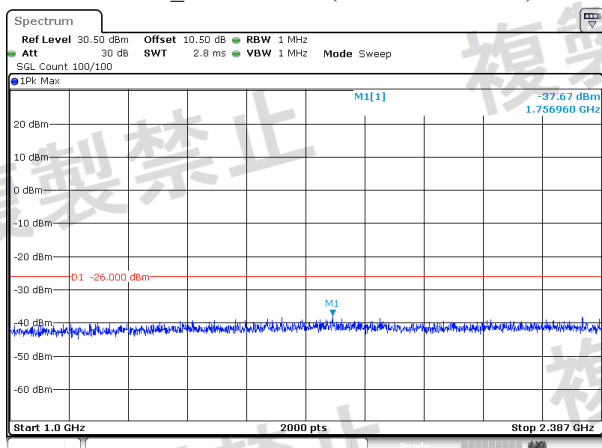
Test Condition: HV

BLE 1M_Low Channel(30MHz~1GHz)



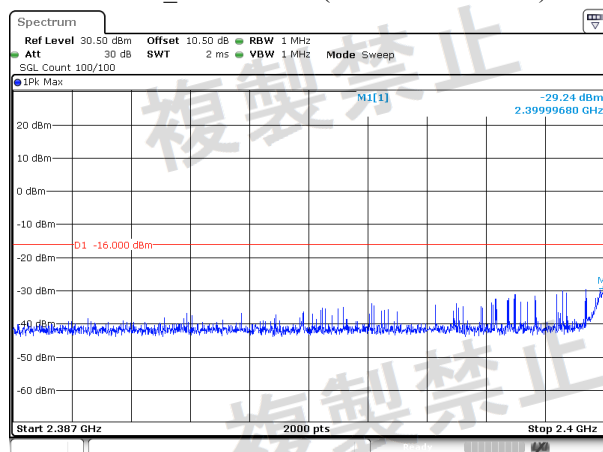
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:46:49

BLE 1M_Low Channel(1GHz~2.387GHz)



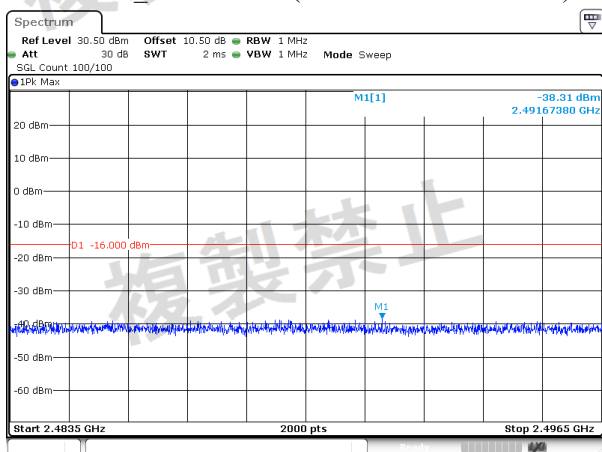
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:46:59

BLE 1M_Low Channel(2.387GHz~2.4GHz)



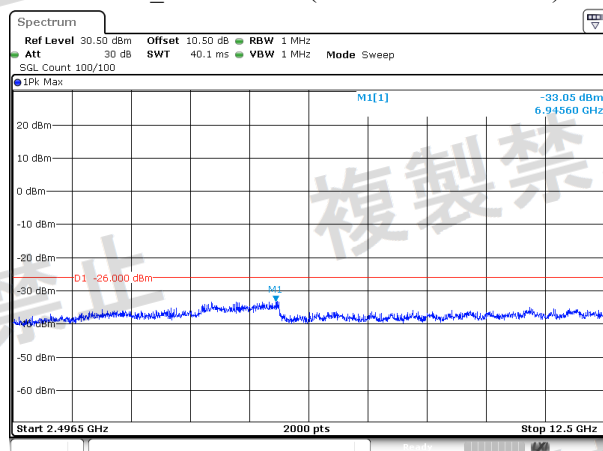
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:47:07

BLE 1M_Low Channel(2.4835GHz~2.4965GHz)



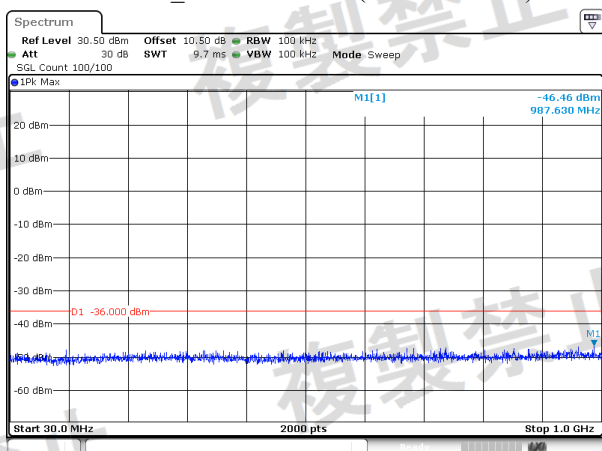
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:47:15

BLE 1M_Low Channel(2.4965GHz~12.5GHz)



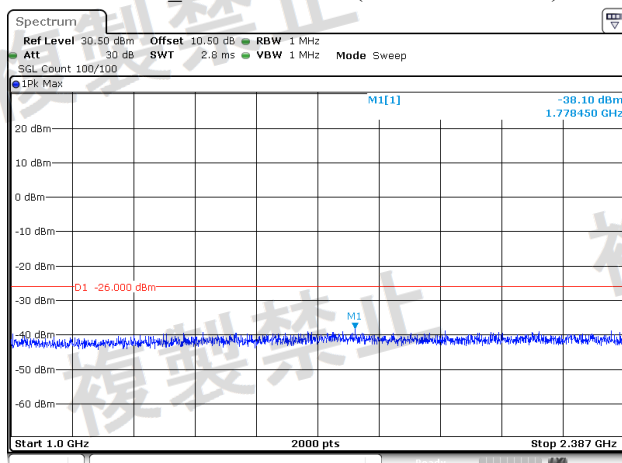
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:47:40

BLE 1M_Middle Channel(30MHz~1GHz)



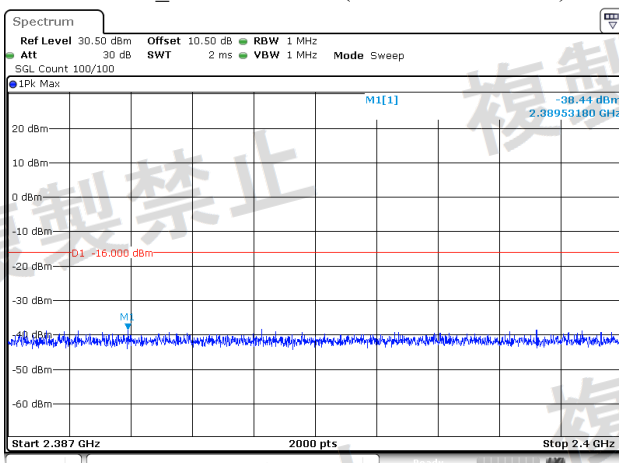
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:49:42

BLE 1M_Middle Channel(1GHz~2.387GHz)



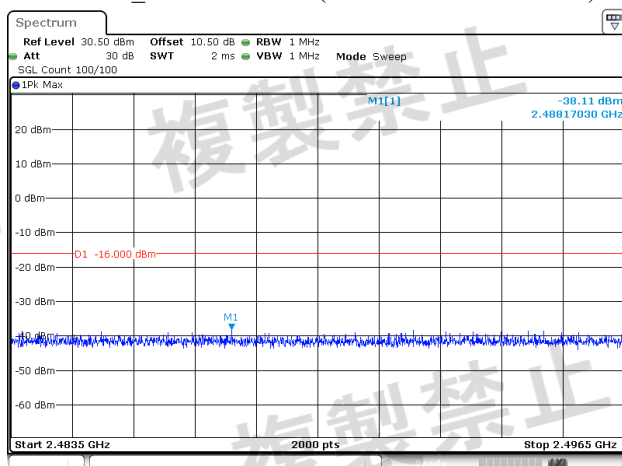
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:49:52

BLE 1M_Middle Channel(2.387GHz~2.4GHz)



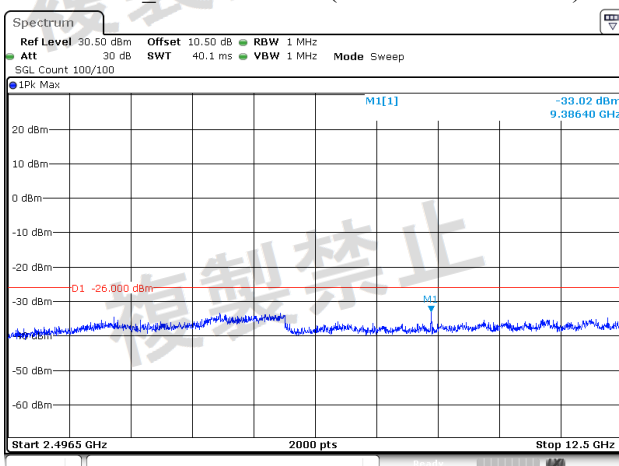
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:49:59

BLE 1M_Middle Channel(2.4835GHz~2.4965GHz)



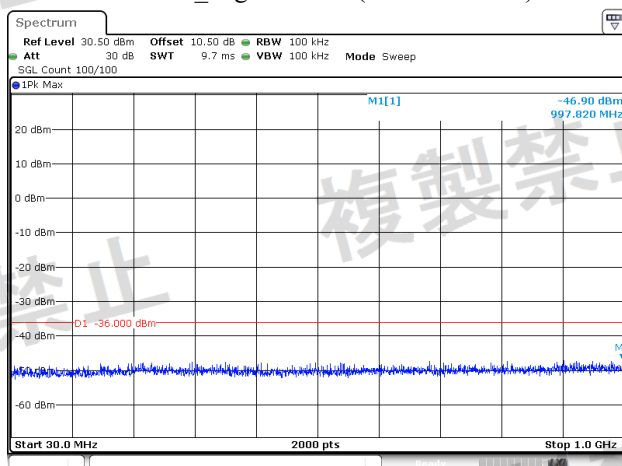
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:50:07

BLE 1M_Middle Channel(2.4965GHz~12.5GHz)



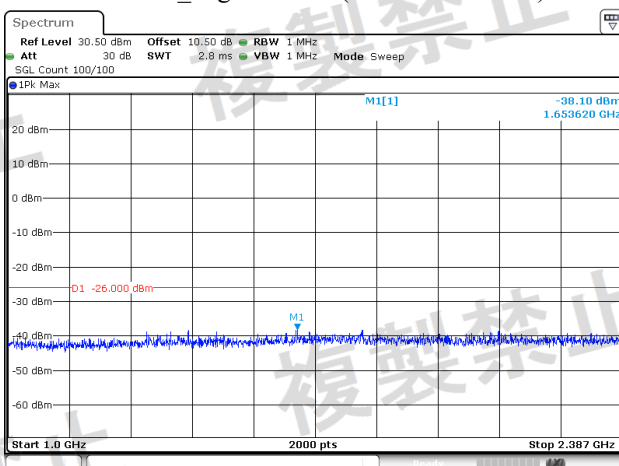
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:50:31

BLE 1M_High Channel(30MHz~1GHz)



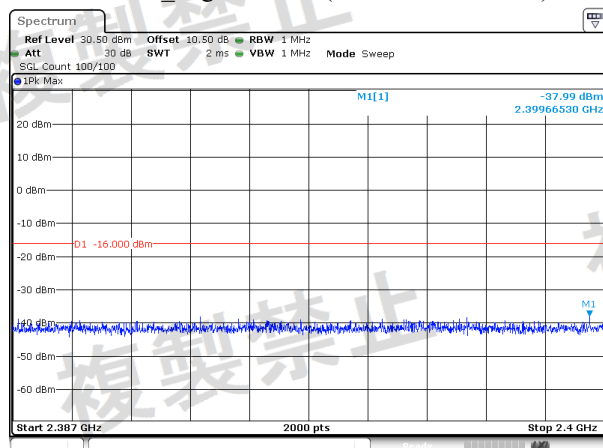
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:51:55

BLE 1M_High Channel(1GHz~2.387GHz)



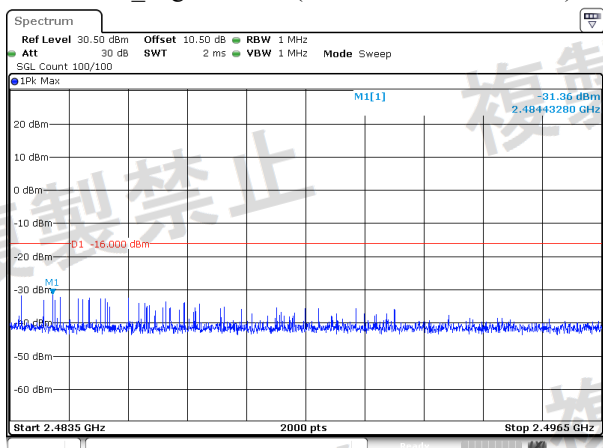
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:52:04

BLE 1M_High Channel(2.387GHz~2.4GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:52:12

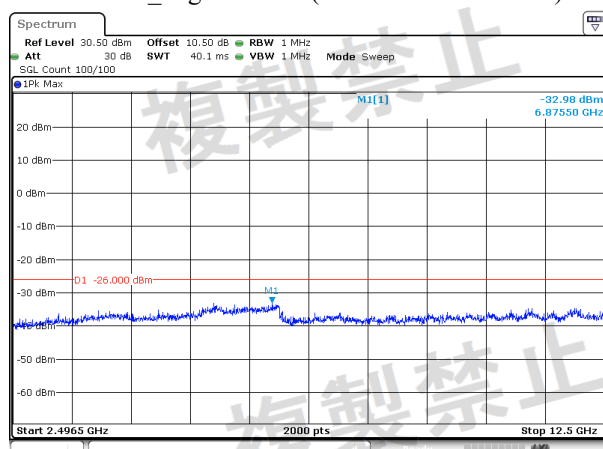
BLE 1M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:52:20

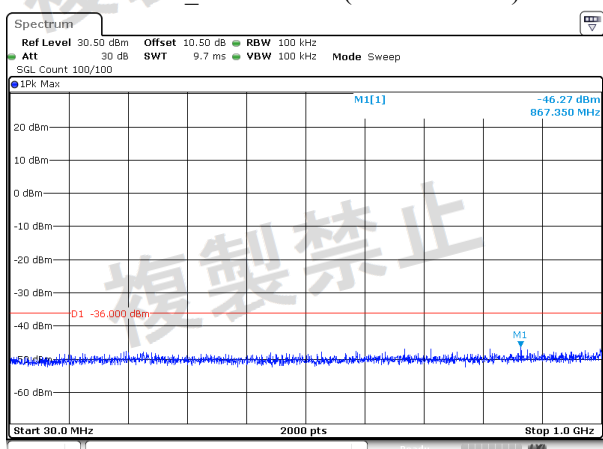
Test Condition: NV

BLE 1M_High Channel(2.4965GHz~12.5GHz)



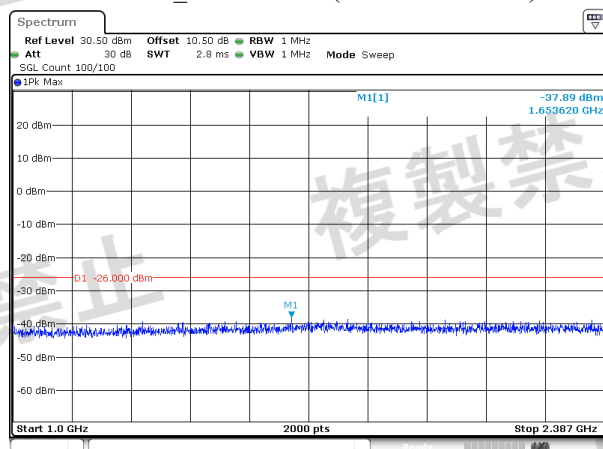
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:52:44

BLE 2M_Low Channel(30MHz~1GHz)



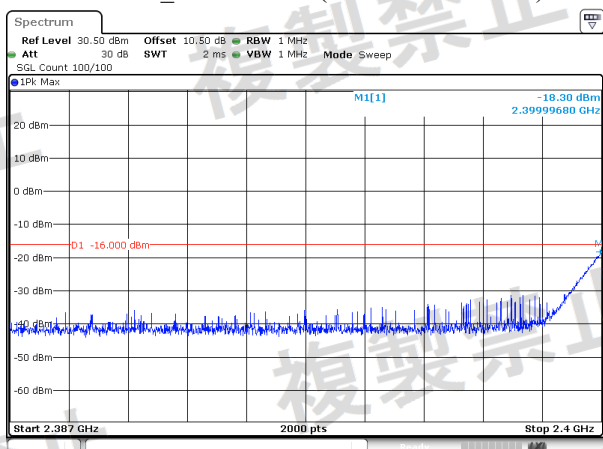
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:46:58

BLE 2M_Low Channel(1GHz~2.387GHz)



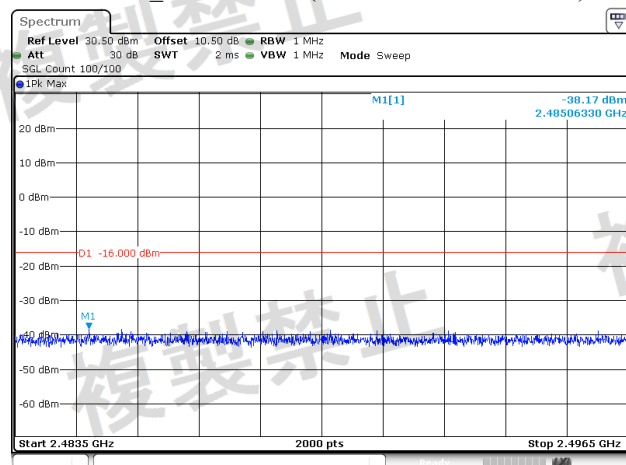
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:47:07

BLE 2M_Low Channel(2.387GHz~2.4GHz)



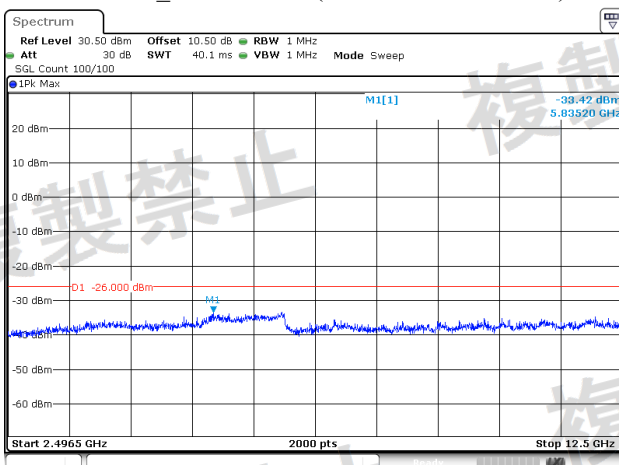
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:47:14

BLE 2M_Low Channel(2.4835GHz~2.4965GHz)



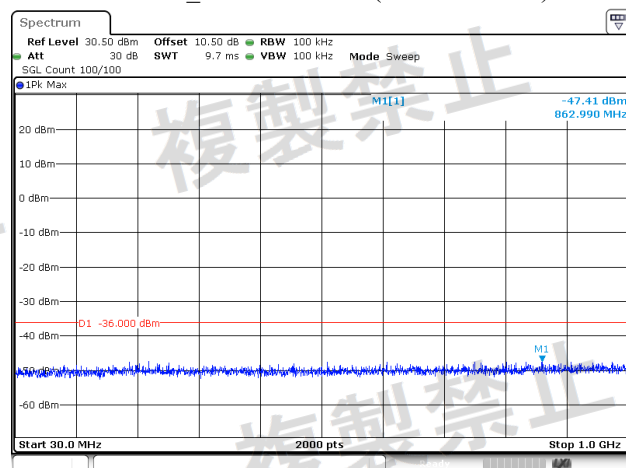
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:47:22

BLE 2M_Low Channel(2.4965GHz~12.5GHz)



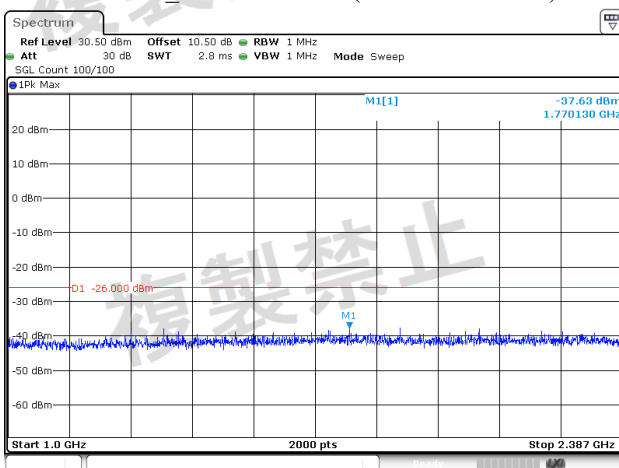
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:47:46

BLE 2M_Middle Channel(30MHz~1GHz)



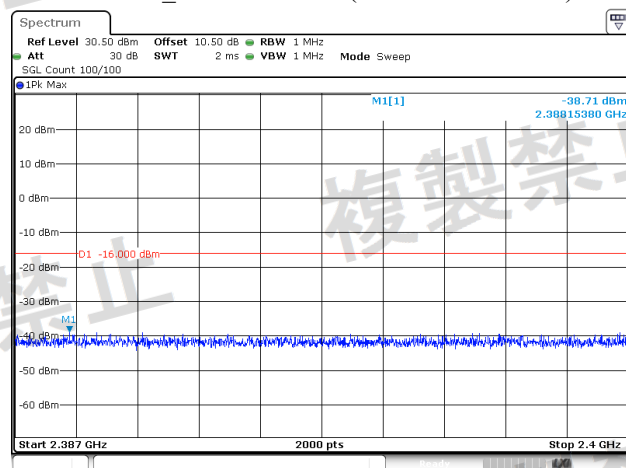
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:49:24

BLE 2M_Middle Channel(1GHz~2.387GHz)



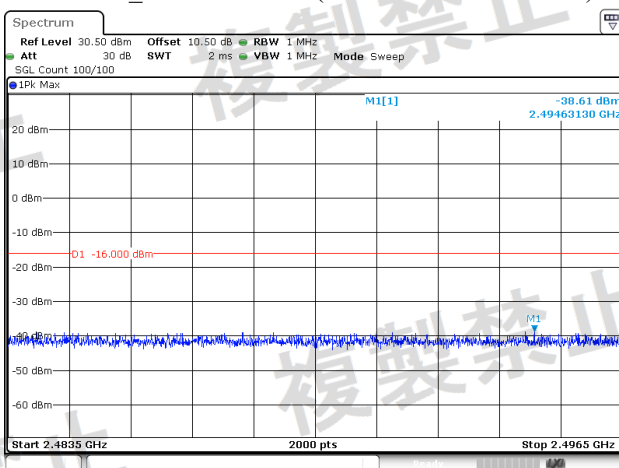
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:49:34

BLE 2M_Middle Channel(2.387GHz~2.4GHz)



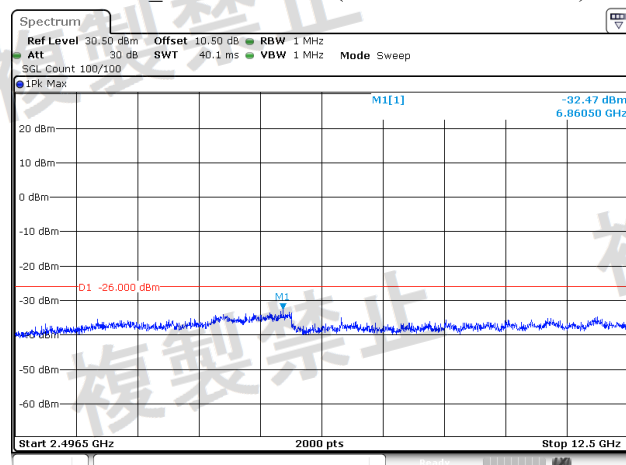
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:49:41

BLE 2M_Middle Channel(2.4835GHz~2.4965GHz)



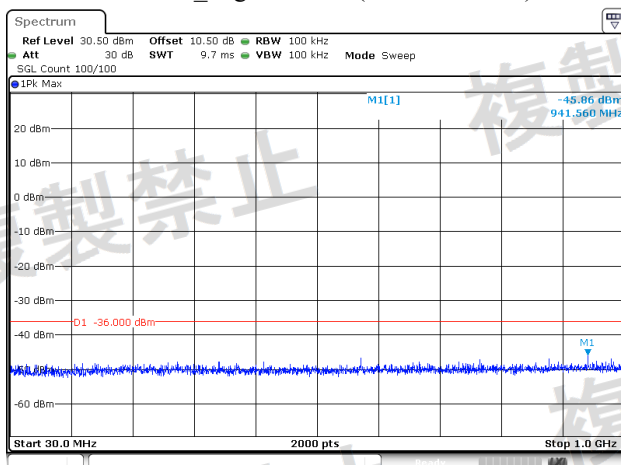
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:49:49

BLE 2M_Middle Channel(2.4965GHz~12.5GHz)



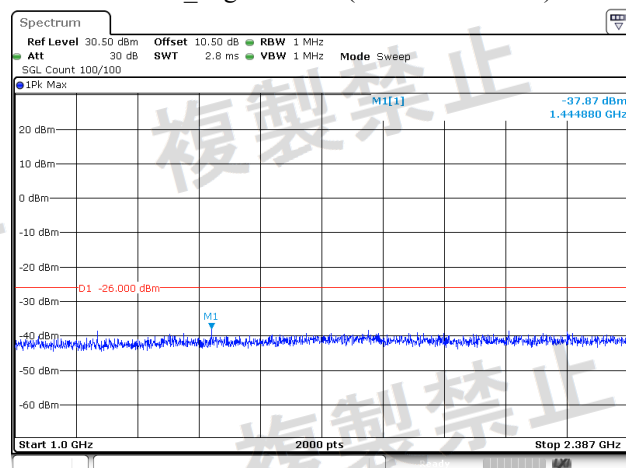
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:50:13

BLE 2M_High Channel(30MHz~1GHz)



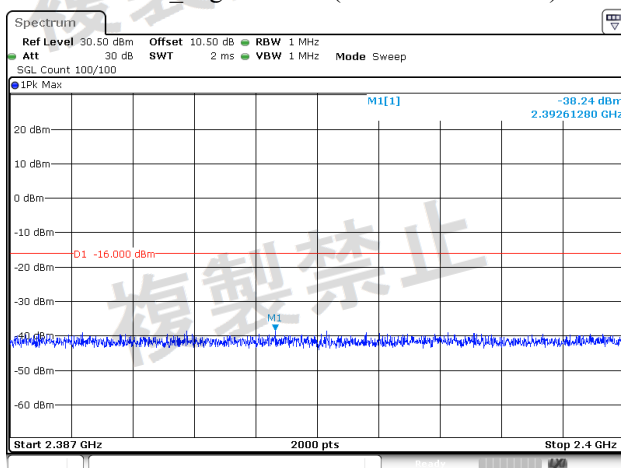
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:51:31

BLE 2M_High Channel(1GHz~2.387GHz)



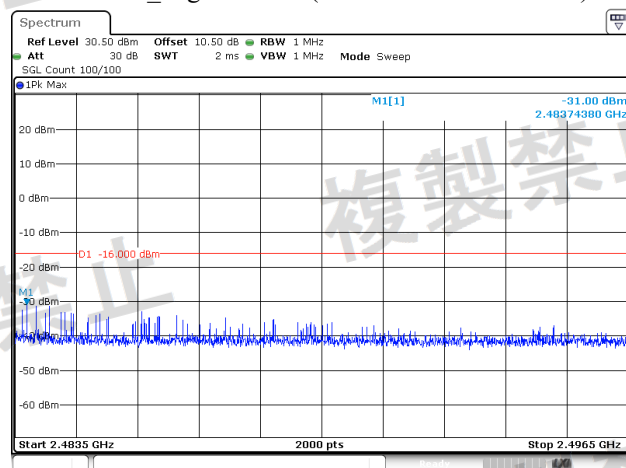
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:51:40

BLE 2M_High Channel(2.387GHz~2.4GHz)



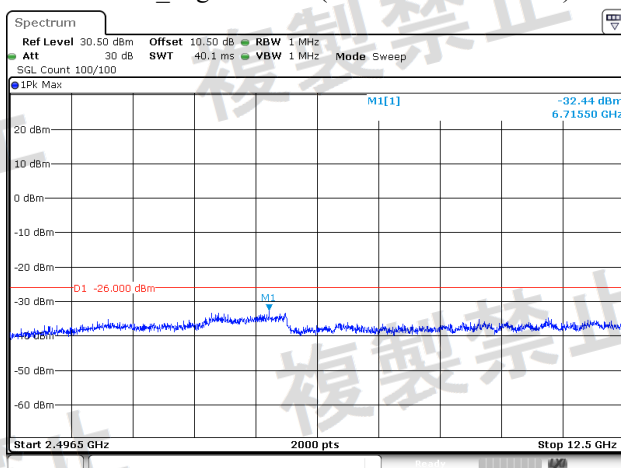
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:51:48

BLE 2M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:51:55

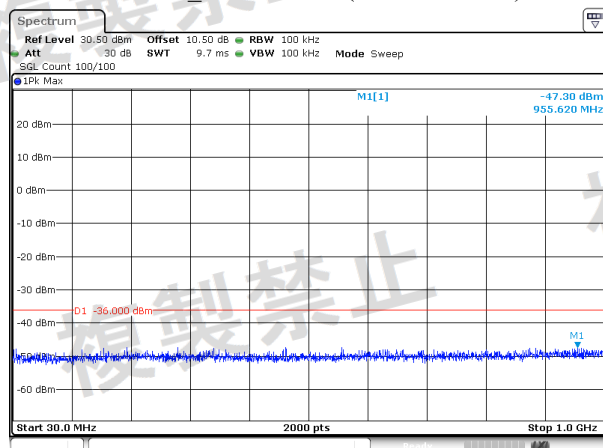
BLE 2M_High Channel(2.4965GHz~12.5GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 11:52:19

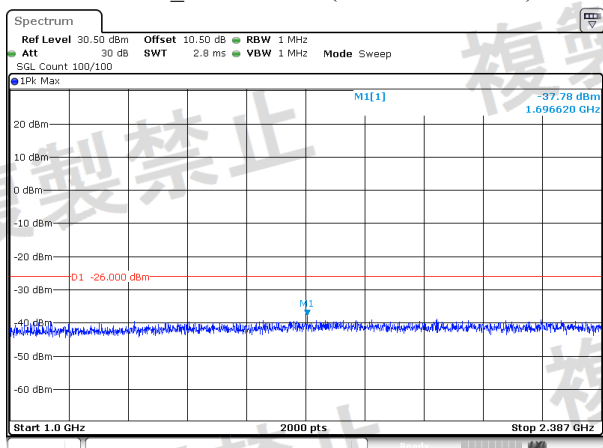
Test Condition: LV

BLE 2M_Low Channel(30MHz~1GHz)



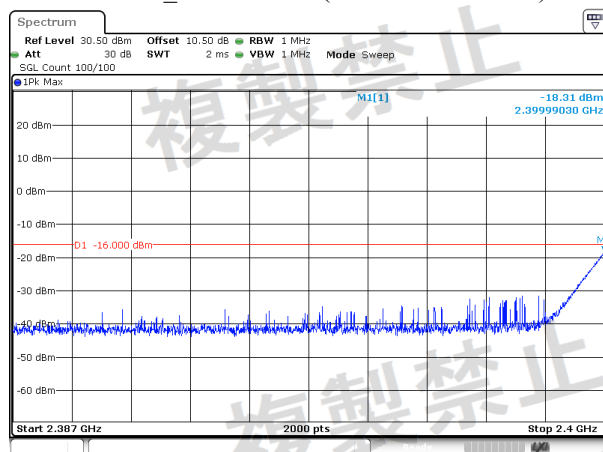
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:14:41

BLE 2M_Low Channel(1GHz~2.387GHz)



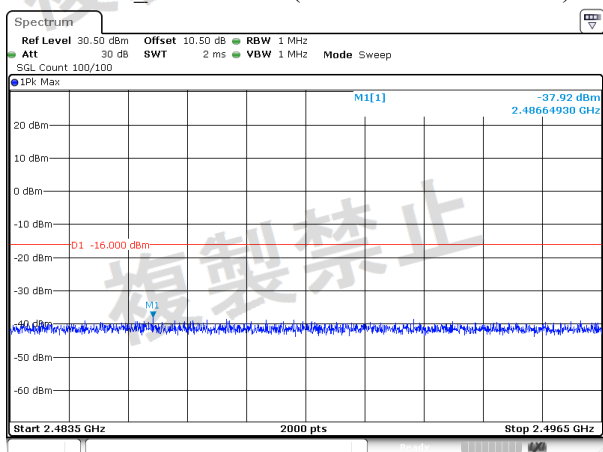
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:14:50

BLE 2M_Low Channel(2.387GHz~2.4GHz)



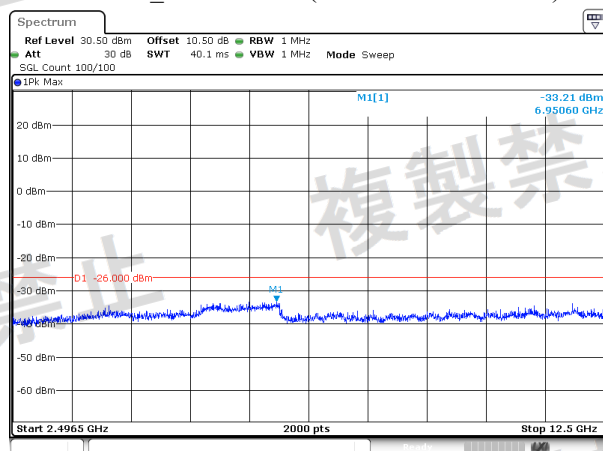
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:14:58

BLE 2M_Low Channel(2.4835GHz~2.4965GHz)



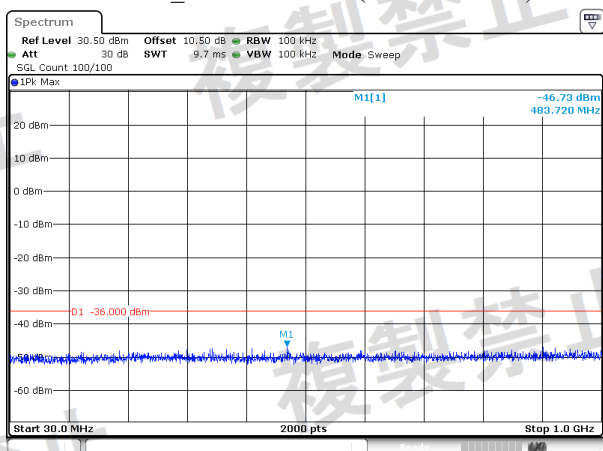
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:15:06

BLE 2M_Low Channel(2.4965GHz~12.5GHz)



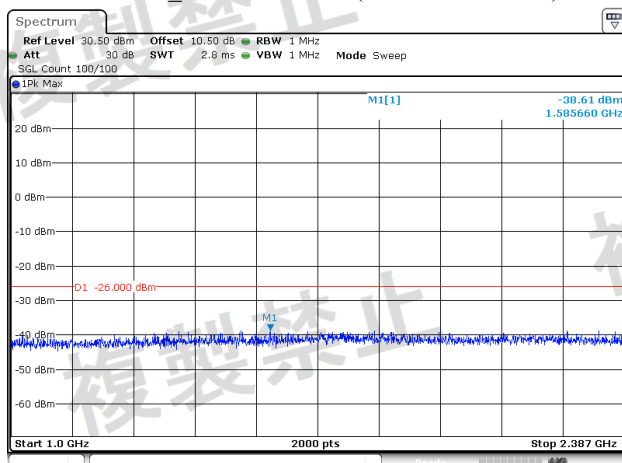
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:15:29

BLE 2M_Middle Channel(30MHz~1GHz)



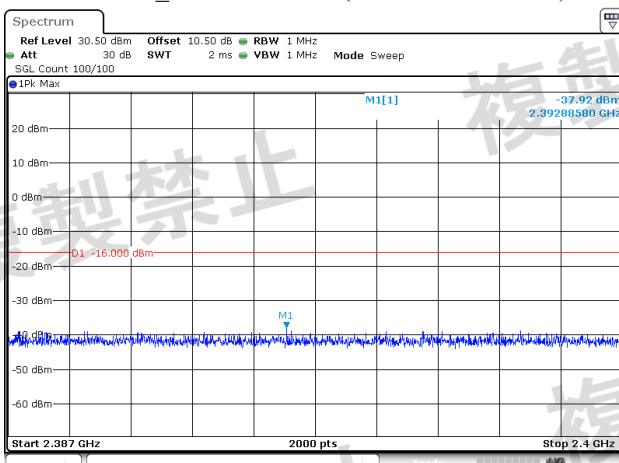
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:17:29

BLE 2M_Middle Channel(1GHz~2.387GHz)



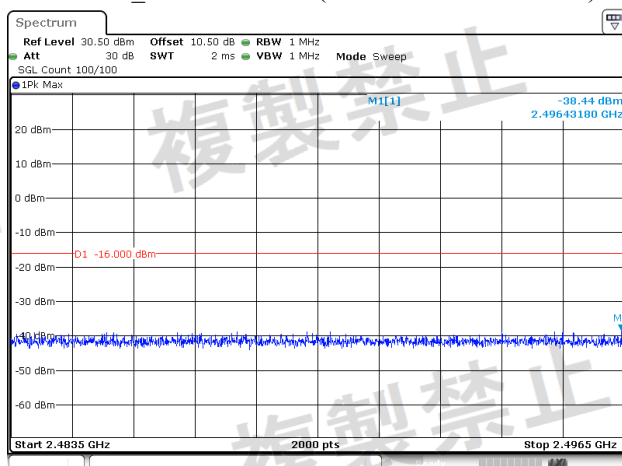
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:17:38

BLE 2M_Middle Channel(2.387GHz~2.4GHz)



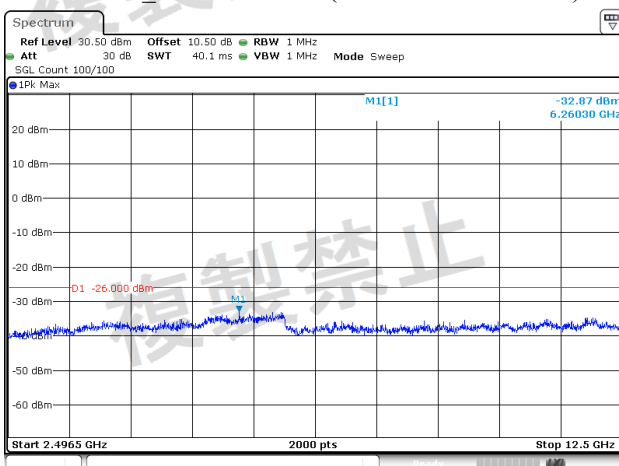
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:17:46

BLE 2M_Middle Channel(2.4835GHz~2.4965GHz)



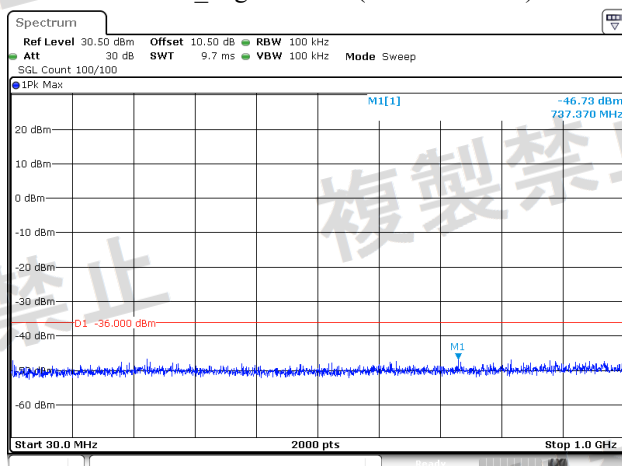
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:17:53

BLE 2M_Middle Channel(2.4965GHz~12.5GHz)



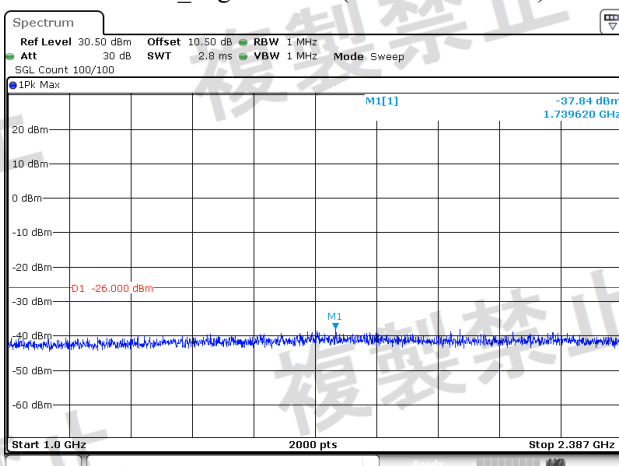
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:18:17

BLE 2M_High Channel(30MHz~1GHz)



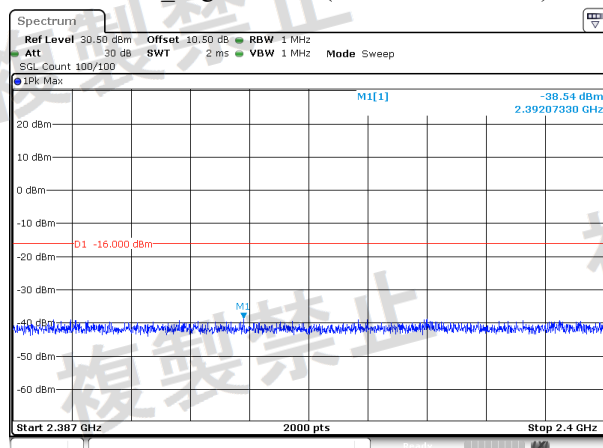
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:36:15

BLE 2M_High Channel(1GHz~2.387GHz)



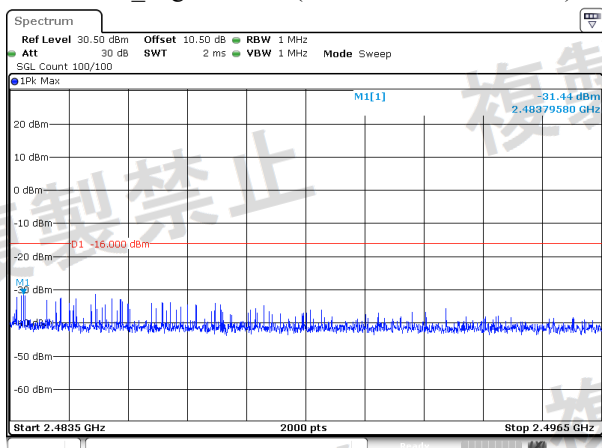
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:36:24

BLE 2M_High Channel(2.387GHz~2.4GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:36:31

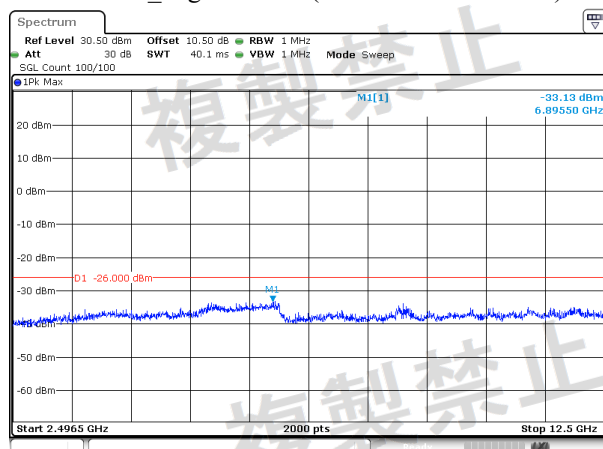
BLE 2M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:36:39

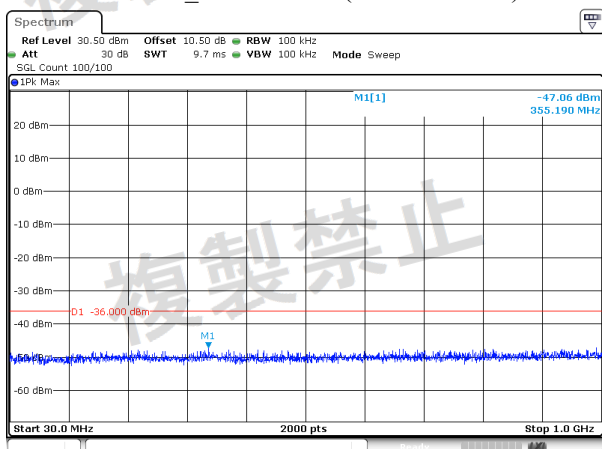
Test Condition: HV

BLE 2M_High Channel(2.4965GHz~12.5GHz)



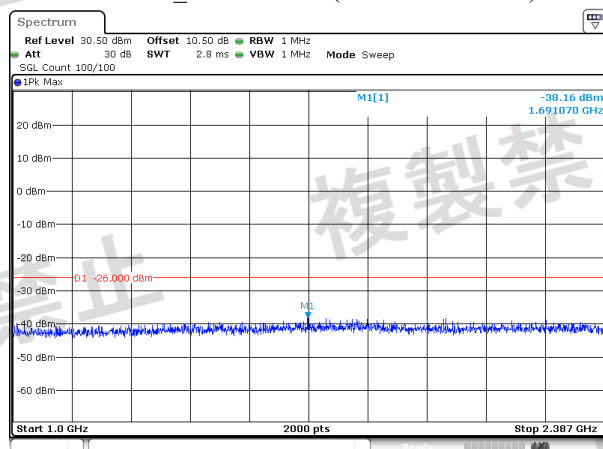
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:37:04

BLE 2M_Low Channel(30MHz~1GHz)



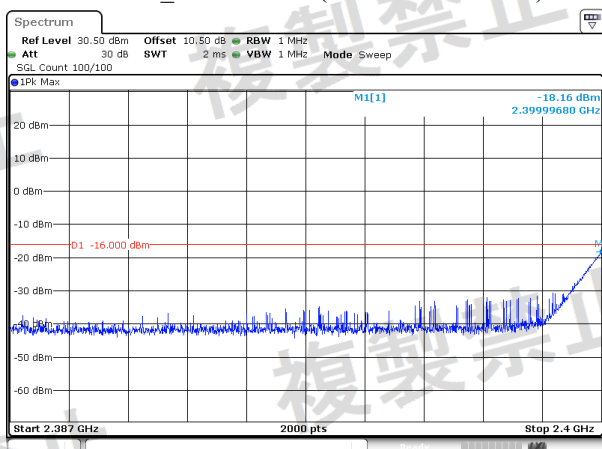
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:54:20

BLE 2M_Low Channel(1GHz~2.387GHz)



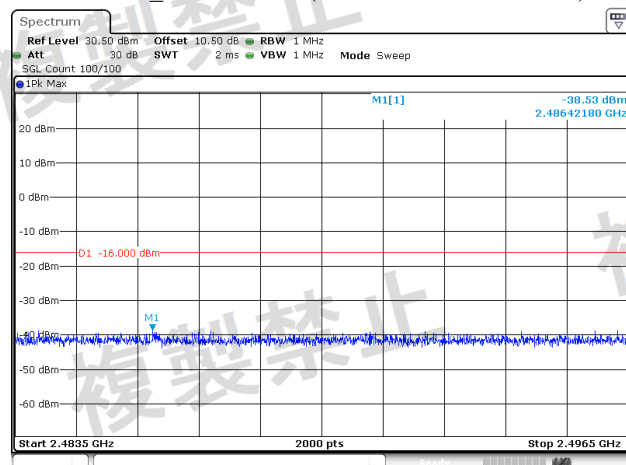
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:54:29

BLE 2M_Low Channel(2.387GHz~2.4GHz)



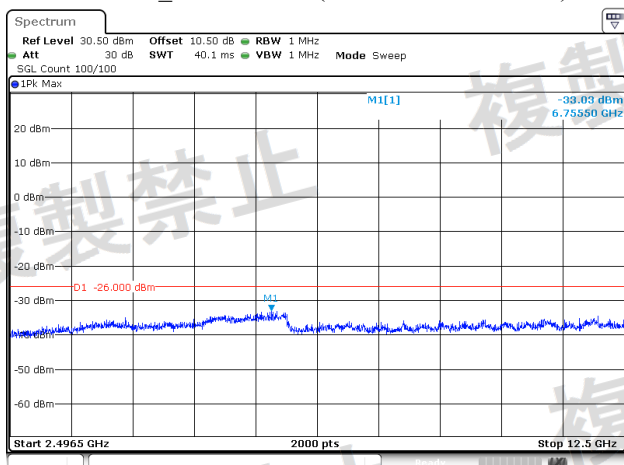
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:54:36

BLE 2M_Low Channel(2.4835GHz~2.4965GHz)



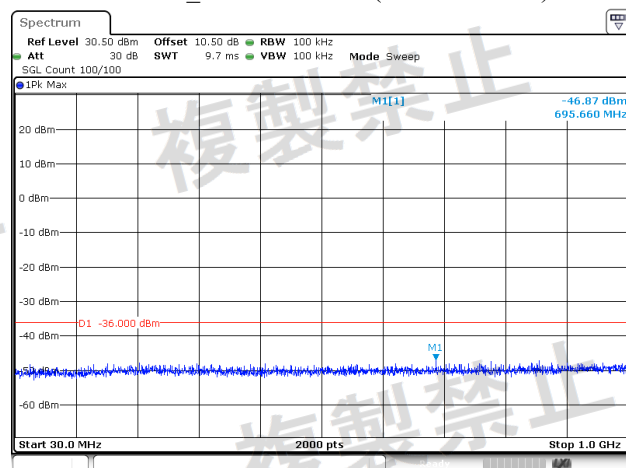
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:54:44

BLE 2M_Low Channel(2.4965GHz~12.5GHz)



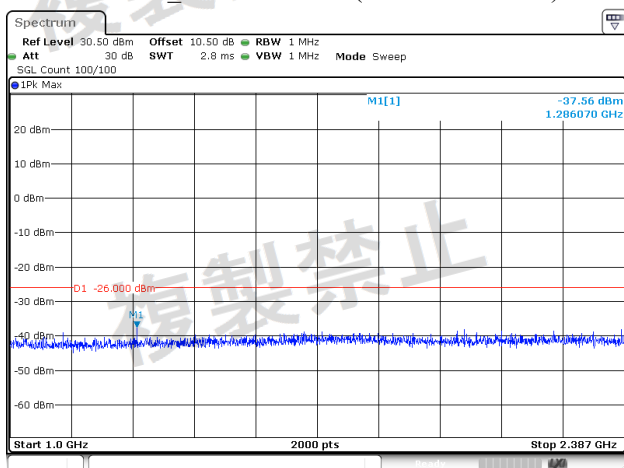
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:55:08

BLE 2M_Middle Channel(30MHz~1GHz)



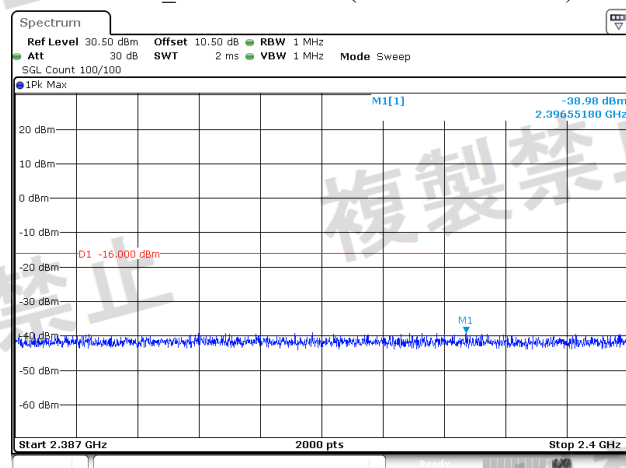
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:57:03

BLE 2M_Middle Channel(1GHz~2.387GHz)



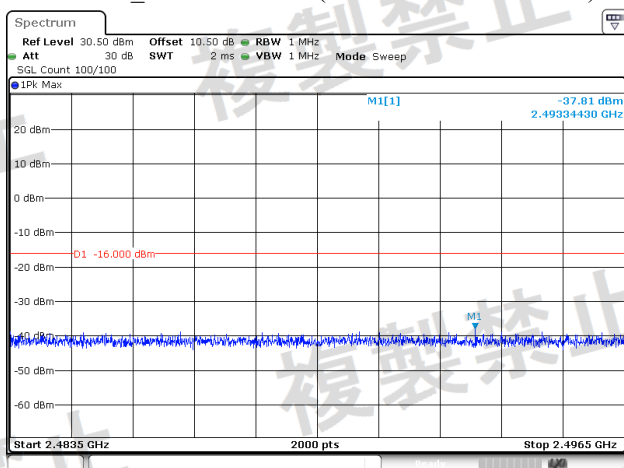
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:57:13

BLE 2M_Middle Channel(2.387GHz~2.4GHz)



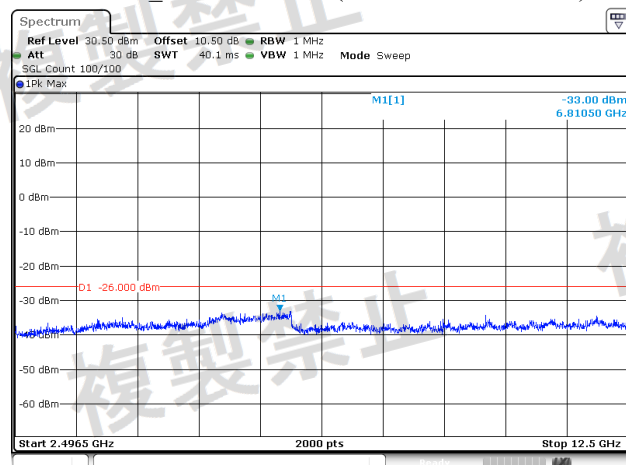
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:57:21

BLE 2M_Middle Channel(2.4835GHz~2.4965GHz)



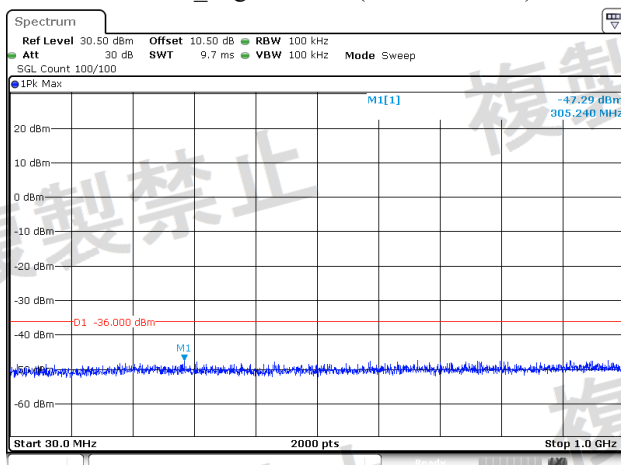
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:57:29

BLE 2M_Middle Channel(2.4965GHz~12.5GHz)



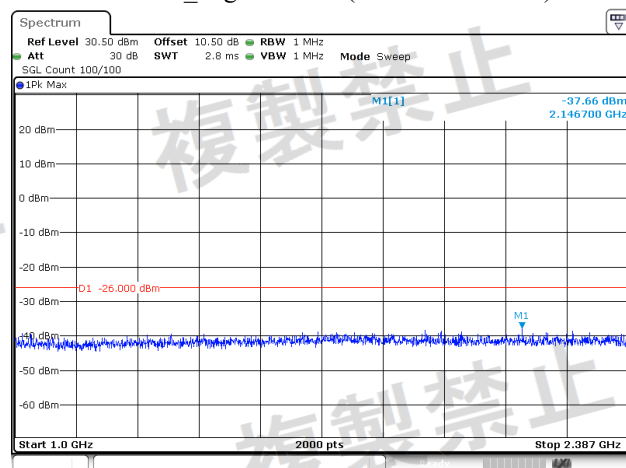
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:57:53

BLE 2M_High Channel(30MHz~1GHz)



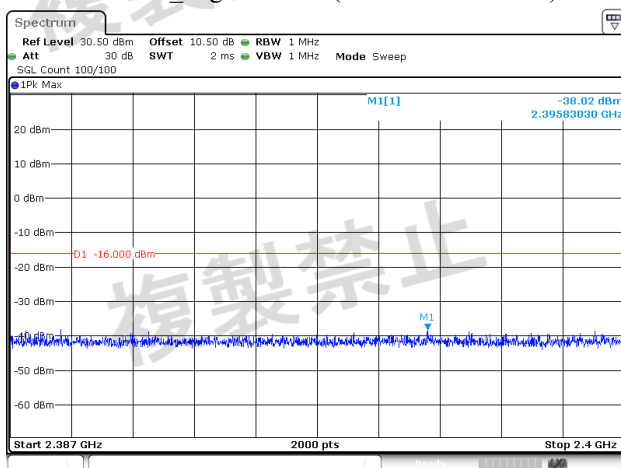
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:59:29

BLE 2M_High Channel(1GHz~2.387GHz)



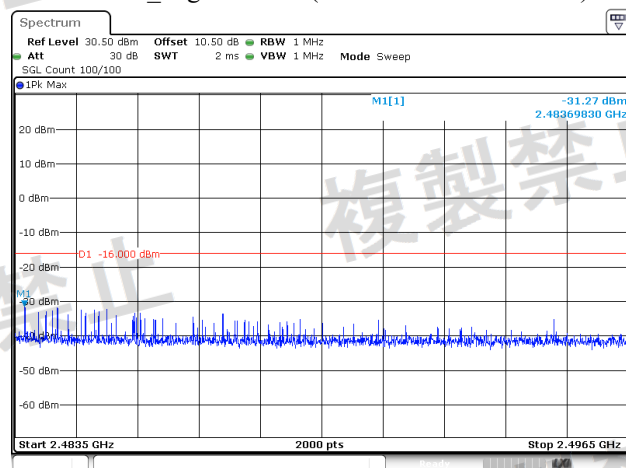
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:59:38

BLE 2M_High Channel(2.387GHz~2.4GHz)



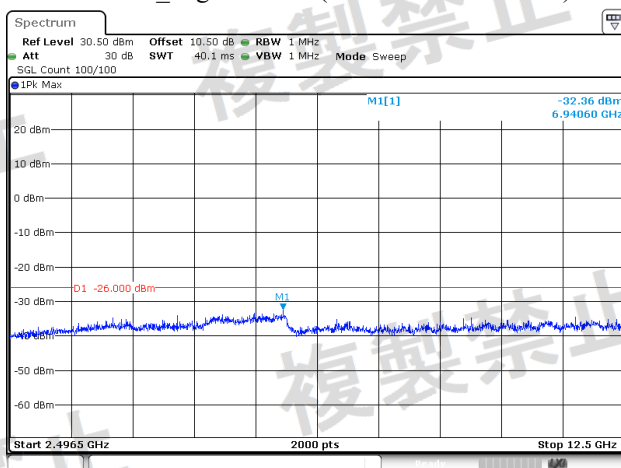
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:59:45

BLE 2M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 14:59:53

BLE 2M_High Channel(2.4965GHz~12.5GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 15:00:17

Antenna Output Power and Output Power Tolerance**Test Information:**

Sample No.:	3BRX-2	Test Date:	2025/11/10
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	26.2	Relative Humidity: (%)	53	ATM Pressure: (kPa)	100.7
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Test Condition: NV

Mode	Antenna gain (dBi)	Declared power (mW)
BLE 1M	3.47	2.0
BLE 2M		2.0

Mode	Channel	Conducted power(dBm)	Antenna output power(mW)		Antenna output tolerance(%)		EIRP (dBm)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
BLE 1M	Low	2.65	1.841	≤ 10	-7.96	-80~+20	6.12	≤ 12.14	Pass
	Middle	2.59	1.816		-9.22		6.06		Pass
	High	2.50	1.778		-11.09		5.97		Pass
BLE 2M	Low	2.07	1.611	≤ 10	-19.47	-80~+20	5.54	≤ 12.14	Pass
	Middle	2.01	1.589		-20.57		5.48		Pass
	High	1.92	1.556		-22.20		5.39		Pass

Test Condition: LV

Mode	Antenna gain (dBi)	Declared power (mW)
BLE 1M	3.47	2.0
BLE 2M	3.47	2.0

Mode	Channel	Conducted power(dBm)	Antenna output power(mW)		Antenna output tolerance(%)		EIRP (dBm)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
BLE 1M	Low	2.68	1.854	≤ 10	-7.32	-80~+20	6.15	≤ 12.14	Pass
	Middle	2.61	1.824		-8.81		6.08		Pass
	High	2.47	1.766		-11.70		5.94		Pass
BLE 2M	Low	2.22	1.667	≤ 10	-16.64	-80~+20	5.69	≤ 12.14	Pass
	Middle	2.01	1.589		-20.57		5.48		Pass
	High	2.00	1.585		-20.76		5.47		Pass

Test Condition: HV

Mode	Antenna gain (dBi)	Declared power (mW)
BLE 1M	3.47	2.0
BLE 2M		2.0

Mode	Channel	Conducted power(dBm)	Antenna output power(mW)		Antenna output tolerance(%)		EIRP (dBm)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
BLE 1M	Low	2.69	1.858	≤ 10	-7.11	-80~+20	6.16	≤ 12.14	Pass
	Middle	2.59	1.816		-9.22		6.06		Pass
	High	2.47	1.766		-11.70		5.94		Pass
BLE 2M	Low	2.23	1.671	≤ 10	-16.45	-80~+20	5.70	≤ 12.14	Pass
	Middle	2.13	1.633		-18.35		5.60		Pass
	High	1.98	1.578		-21.12		5.45		Pass

Note:

$$\text{Antenna output power(mW)} = 10^{\{\text{Conducted power(dBm)} / 10\}}$$

$$\text{Antenna output power tolerance(\%)} = (\text{Antenna output power} - \text{Declared power}) / \text{Declared power} * 100\%$$

$$\text{Antenna output power(dBm)} = 10 * \log_{10}\{\text{Antenna output power(mW)}\}$$

$$\text{EIRP(dBm)} = \text{Antenna output power(dBm)} + \text{Antenna gain.}$$

Receiver Spurious Emission and Unwanted Emission Intensity**Test Information:**

Sample No.:	3BRX-2	Test Date:	2025/11/10
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	26.2	Relative Humidity: (%)	53	ATM Pressure: (kPa)	100.7
-----------------------------	------	----------------------------------	----	-------------------------------	-------

Test Condition: NV

Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start(MHz)	Stop(MHz)					
BLE 1M	Low	Band I (100kHz)	30	1000	738.997	-66.53	0.222	4	Pass
		Band II (1MHz)	1000	12500	6969.36	-52.83	5.212	20	Pass
	Middle	Band I (100kHz)	30	1000	994.689	-66.83	0.207	4	Pass
		Band II (1MHz)	1000	12500	6823.89	-53.05	4.955	20	Pass
	High	Band I (100kHz)	30	1000	871.548	-66.18	0.241	4	Pass
		Band II (1MHz)	1000	12500	6908.41	-52.83	5.212	20	Pass
BLE 2M	Low	Band I (100kHz)	30	1000	676.287	-66.92	0.203	4	Pass
		Band II (1MHz)	1000	12500	6971.66	-52.84	5.200	20	Pass
	Middle	Band I (100kHz)	30	1000	637.39	-66.85	0.207	4	Pass
		Band II (1MHz)	1000	12500	6996.39	-53.21	4.775	20	Pass
	High	Band I (100kHz)	30	1000	575.164	-67.06	0.197	4	Pass
		Band II (1MHz)	1000	12500	6853.21	-51.69	6.776	20	Pass

Test Condition: LV

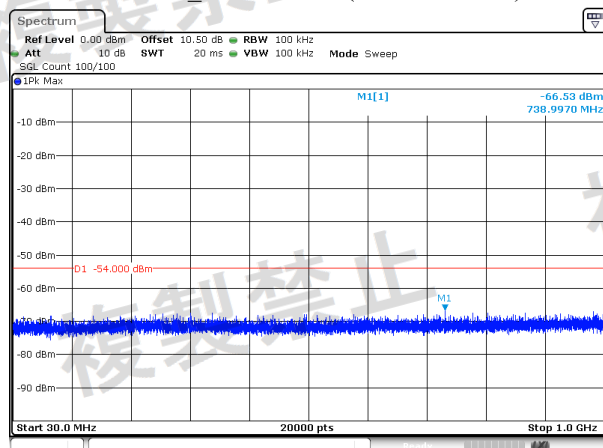
Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start(MHz)	Stop(MHz)					
BLE 1M	Low	Band I (100kHz)	30	1000	668.818	-66.86	0.206	4	Pass
		Band II (1MHz)	1000	12500	5890.09	-52.92	5.105	20	Pass
	Middle	Band I (100kHz)	30	1000	644.325	-66.83	0.207	4	Pass
		Band II (1MHz)	1000	12500	6842.86	-52.97	5.047	20	Pass
	High	Band I (100kHz)	30	1000	950.409	-66.74	0.212	4	Pass
		Band II (1MHz)	1000	12500	6977.99	-52.57	5.534	20	Pass
BLE 2M	Low	Band I (100kHz)	30	1000	690.449	-66.81	0.208	4	Pass
		Band II (1MHz)	1000	12500	6821.59	-52.72	5.346	20	Pass
	Middle	Band I (100kHz)	30	1000	926.789	-66.03	0.249	4	Pass
		Band II (1MHz)	1000	12500	6939.46	-53.21	4.775	20	Pass
	High	Band I (100kHz)	30	1000	927.759	-66.87	0.206	4	Pass
		Band II (1MHz)	1000	12500	6783.06	-52.46	5.675	20	Pass

Test Condition: HV

Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start(MHz)	Stop(MHz)					
BLE 1M	Low	Band I (100kHz)	30	1000	348.718	-67.34	0.185	4	Pass
		Band II (1MHz)	1000	12500	6959.01	-52.99	5.023	20	Pass
	Middle	Band I (100kHz)	30	1000	837.404	-66.99	0.200	4	Pass
		Band II (1MHz)	1000	12500	6996.39	-53.02	4.989	20	Pass
	High	Band I (100kHz)	30	1000	981.4	-67.12	0.194	4	Pass
		Band II (1MHz)	1000	12500	2401.56	-50.26	9.419	20	Pass
BLE 2M	Low	Band I (100kHz)	30	1000	797.1	-66.38	0.230	4	Pass
		Band II (1MHz)	1000	12500	1900.16	-49.80	10.471	20	Pass
	Middle	Band I (100kHz)	30	1000	833.766	-66.43	0.228	4	Pass
		Band II (1MHz)	1000	12500	6929.69	-53.06	4.943	20	Pass
	High	Band I (100kHz)	30	1000	955.016	-66.64	0.217	4	Pass
		Band II (1MHz)	1000	12500	6984.89	-52.60	5.495	20	Pass

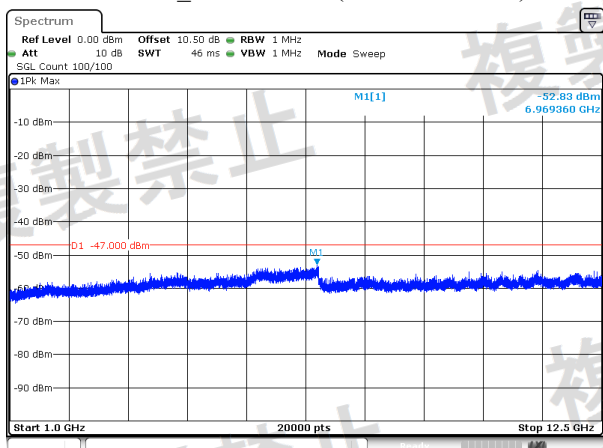
Test Condition: NV

BLE 1M_Low Channel(30MHz~1GHz)



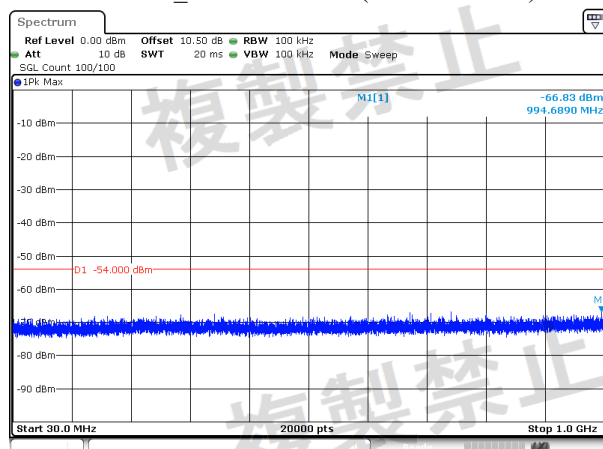
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 12:00:21

BLE 1M_Low Channel(1GHz~12.5GHz)



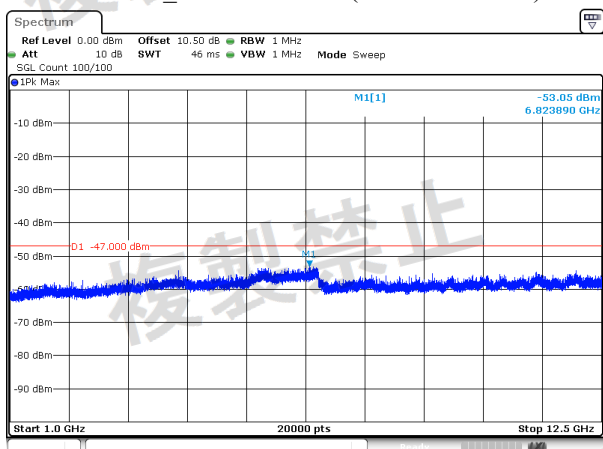
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Date: 10.NOV.2025 12:00:48

BLE 1M_Middle Channel(30MHz~1GHz)



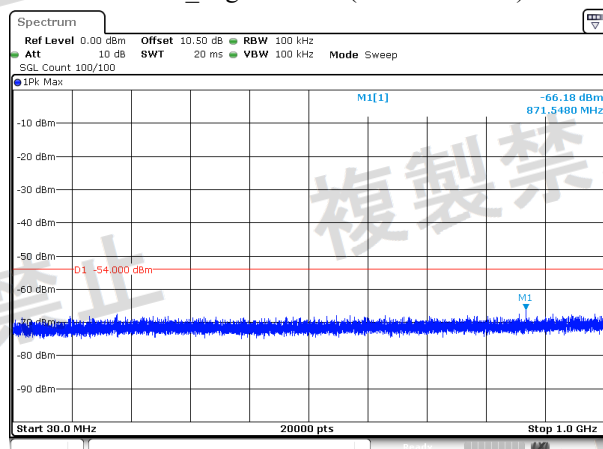
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Date: 10.NOV.2025 12:01:07

BLE 1M_Middle Channel(1GHz~12.5GHz)



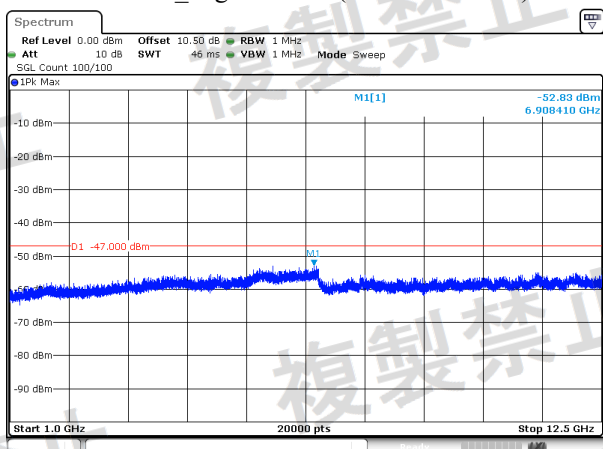
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 12:01:34

BLE 1M_High Channel(30MHz~1GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 12:01:54

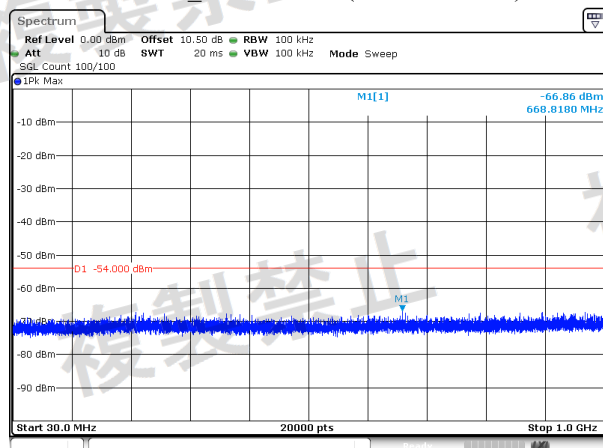
BLE 1M_High Channel(1GHz~12.5GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 12:02:21

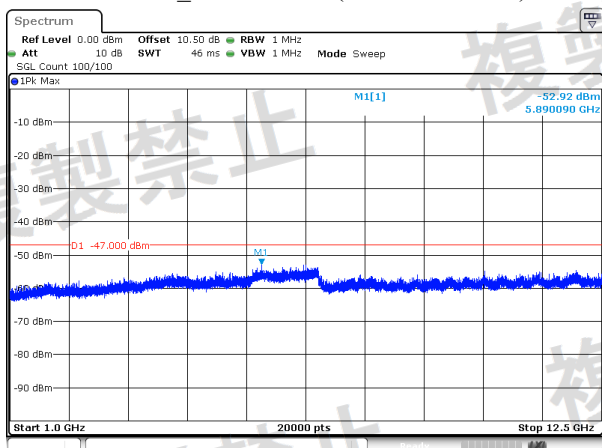
Test Condition: LV

BLE 1M_Low Channel(30MHz~1GHz)



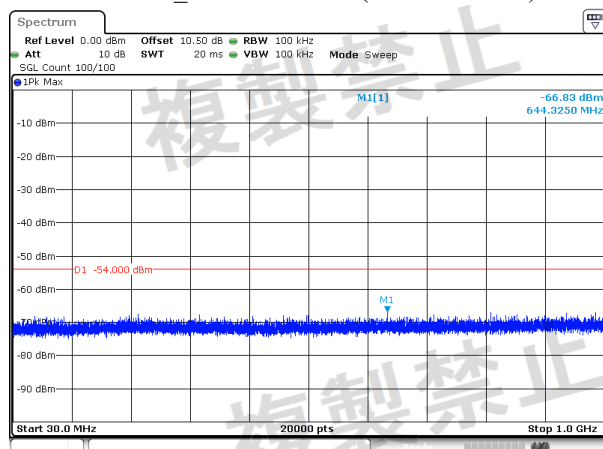
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:41:28

BLE 1M_Low Channel(1GHz~12.5GHz)



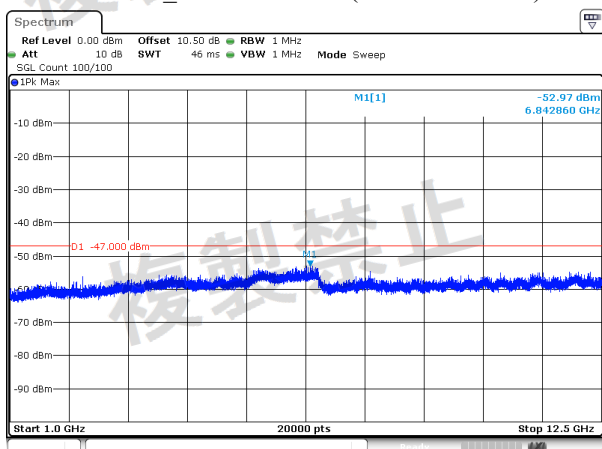
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Date: 10.NOV.2025 13:42:29

BLE 1M_Middle Channel(30MHz~1GHz)



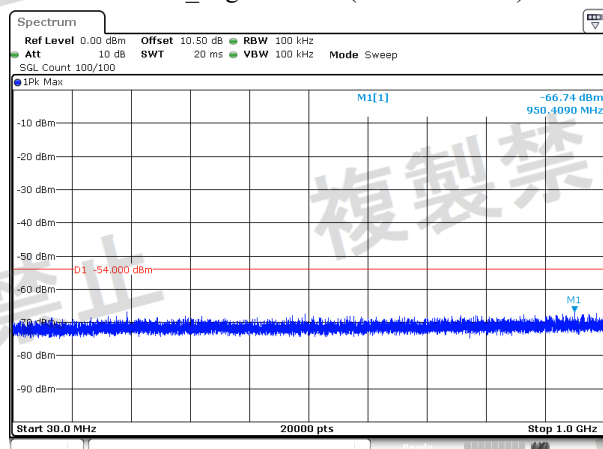
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:42:49

BLE 1M_Middle Channel(1GHz~12.5GHz)



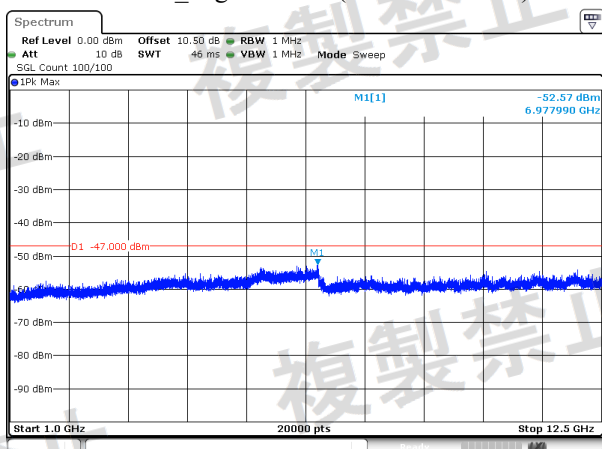
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:43:16

BLE 1M_High Channel(30MHz~1GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:43:43

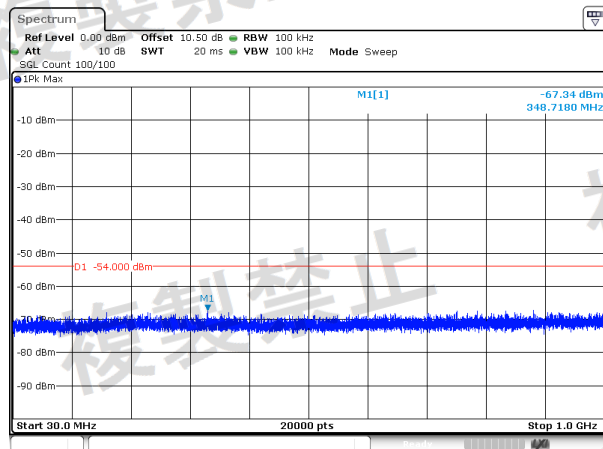
BLE 1M_High Channel(1GHz~12.5GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:44:10

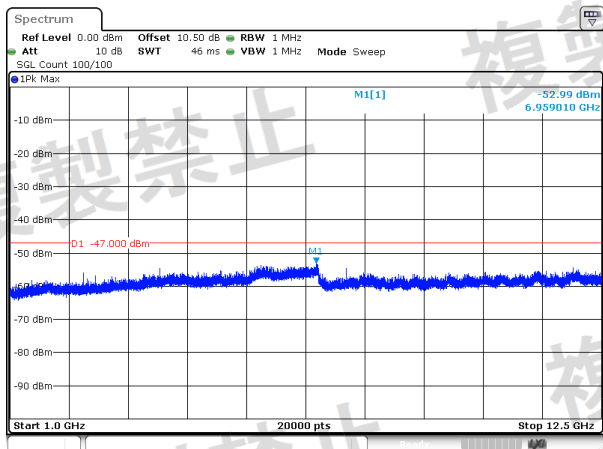
Test Condition: HV

BLE 1M_Low Channel(30MHz~1GHz)



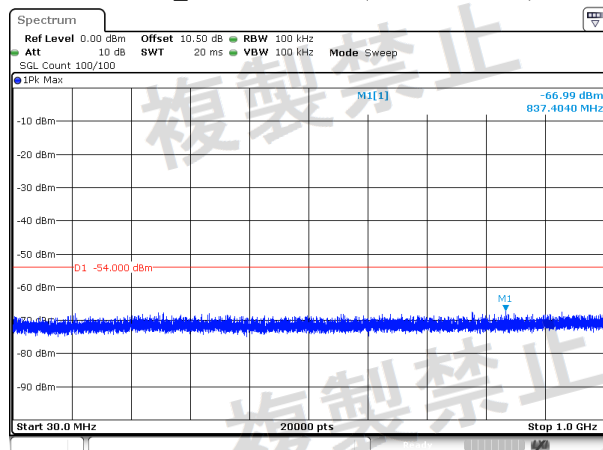
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Date: 10.NOV.2025 13:47:38

BLE 1M_Low Channel(1GHz~12.5GHz)



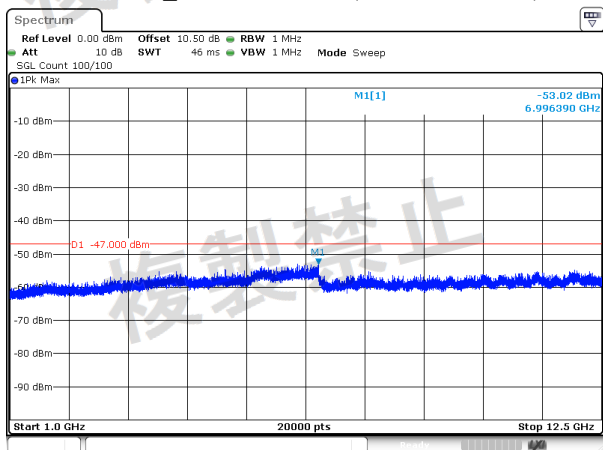
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:48:05

BLE 1M_Middle Channel(30MHz~1GHz)



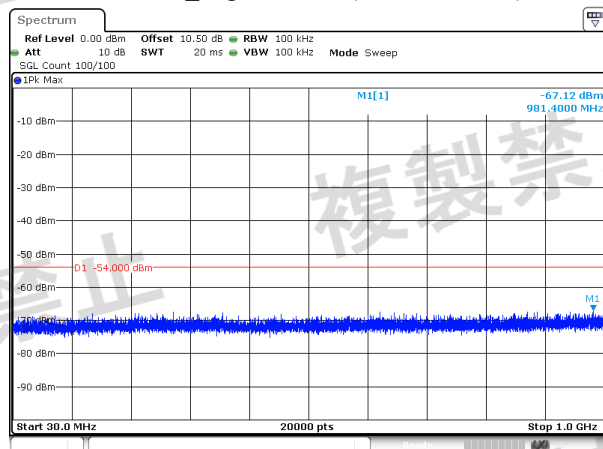
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Date: 10.NOV.2025 13:48:27

BLE 1M_Middle Channel(1GHz~12.5GHz)



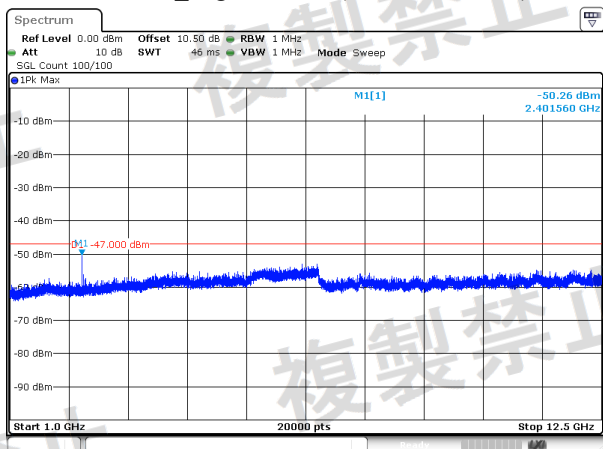
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:48:54

BLE 1M_High Channel(30MHz~1GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:49:15

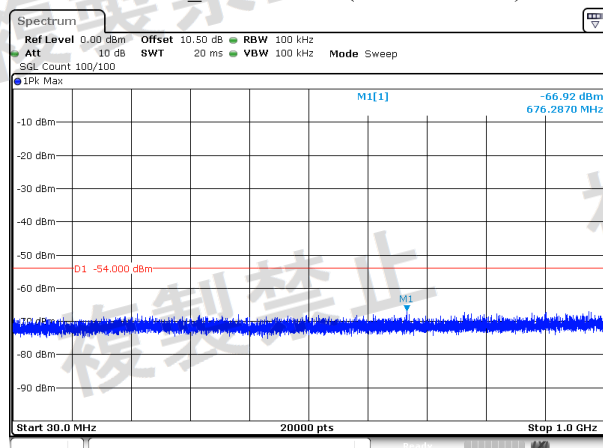
BLE 1M_High Channel(1GHz~12.5GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:49:42

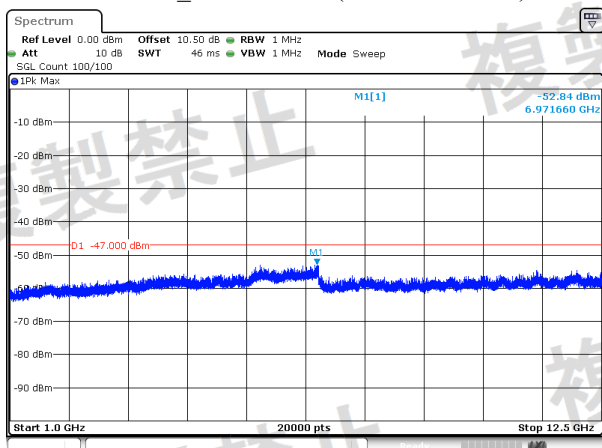
Test Condition: NV

BLE 2M_Low Channel(30MHz~1GHz)



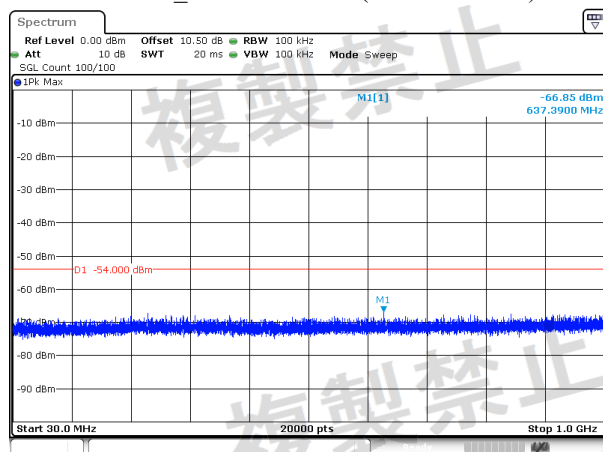
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 12:02:41

BLE 2M_Low Channel(1GHz~12.5GHz)



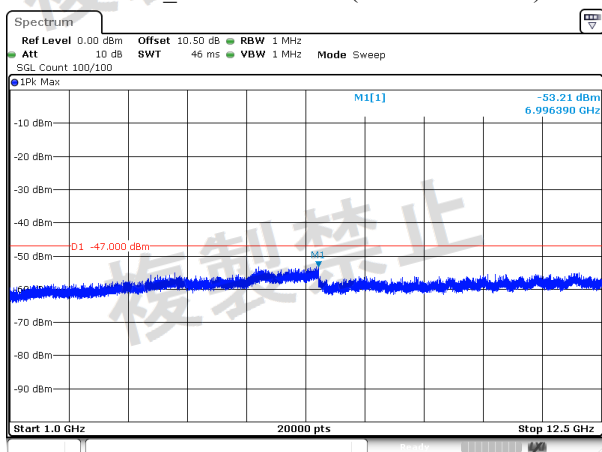
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Date: 10.NOV.2025 12:03:08

BLE 2M_Middle Channel(30MHz~1GHz)



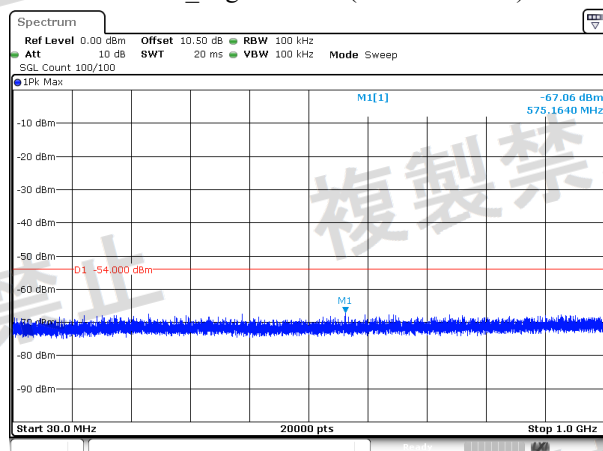
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Date: 10.NOV.2025 13:09:36

BLE 2M_Middle Channel(1GHz~12.5GHz)



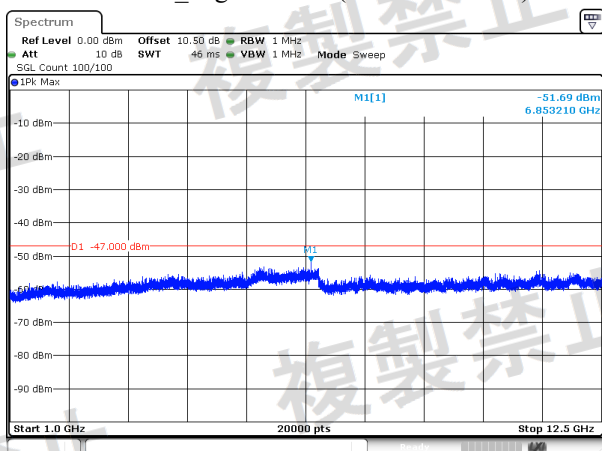
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:10:04

BLE 2M_High Channel(30MHz~1GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:10:23

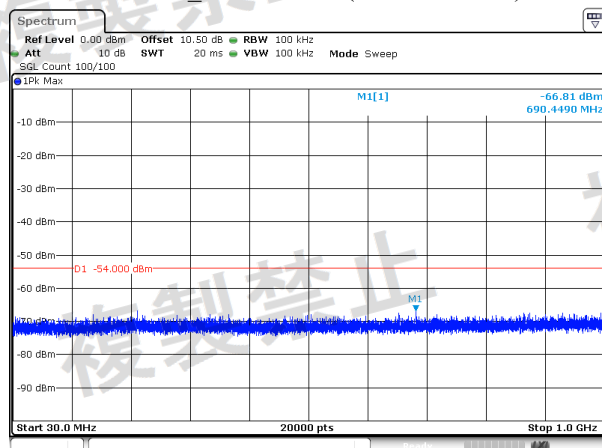
BLE 2M_High Channel(1GHz~12.5GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:12:37

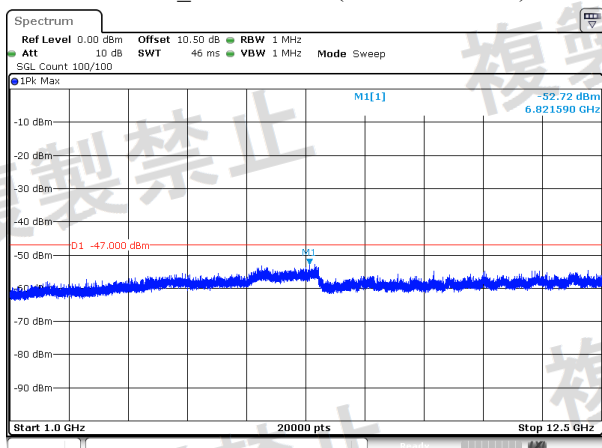
Test Condition: LV

BLE 2M_Low Channel(30MHz~1GHz)



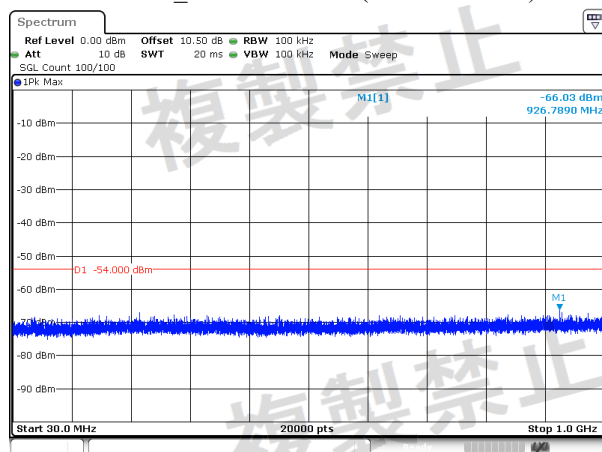
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:44:41

BLE 2M_Low Channel(1GHz~12.5GHz)



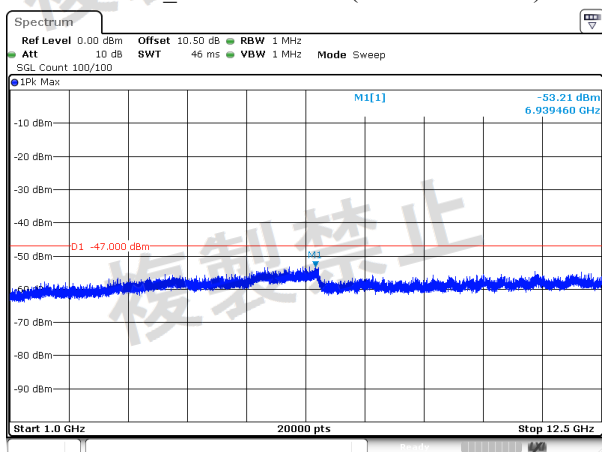
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Date: 10.NOV.2025 13:45:09

BLE 2M_Middle Channel(30MHz~1GHz)



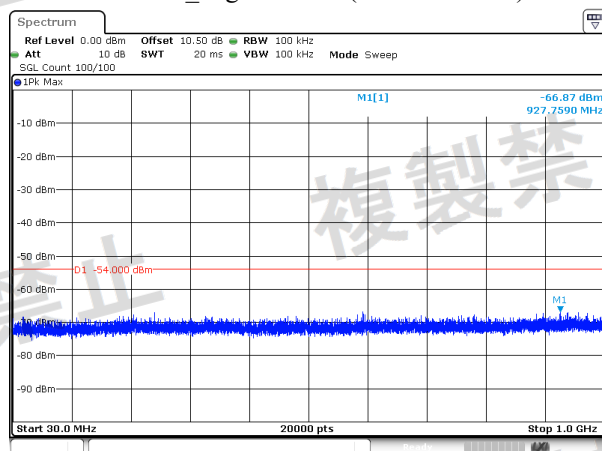
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BLE 2M_Middle Channel(1GHz~12.5GHz)



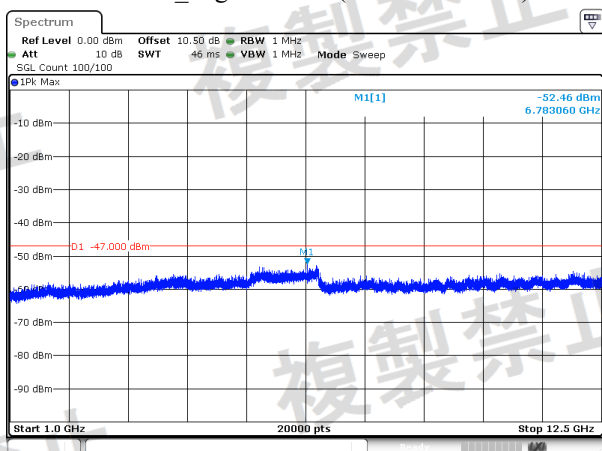
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:45:56

BLE 2M_High Channel(30MHz~1GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:46:18

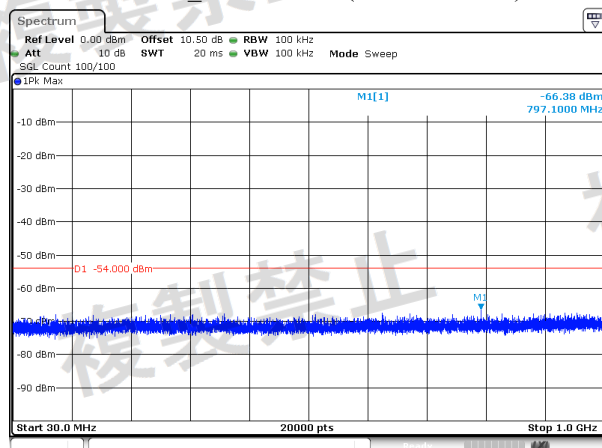
BLE 2M_High Channel(1GHz~12.5GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:46:45

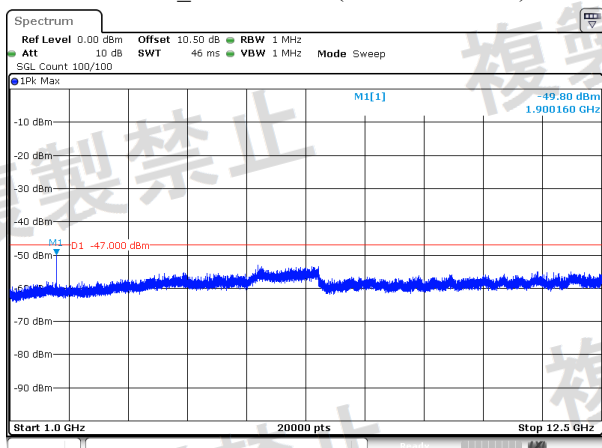
Test Condition: HV

BLE 2M_Low Channel(30MHz~1GHz)



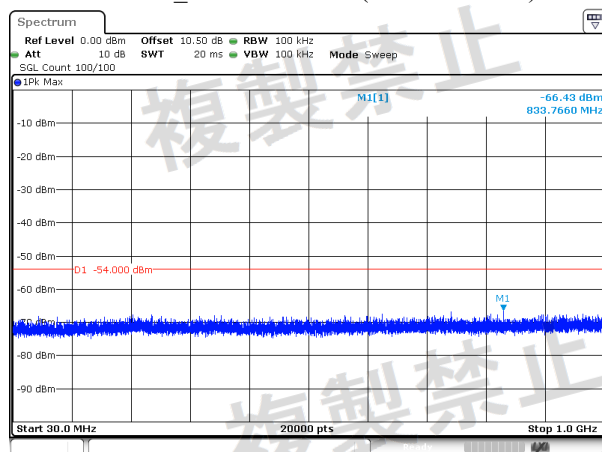
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:50:12

BLE 2M_Low Channel(1GHz~12.5GHz)



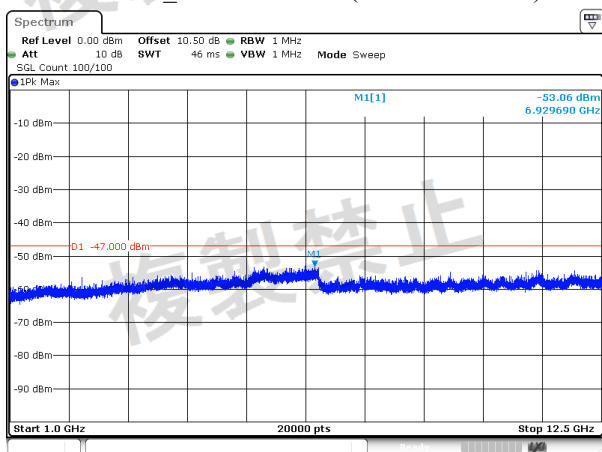
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Date: 10.NOV.2025 13:50:13

BLE 2M_Middle Channel(30MHz~1GHz)



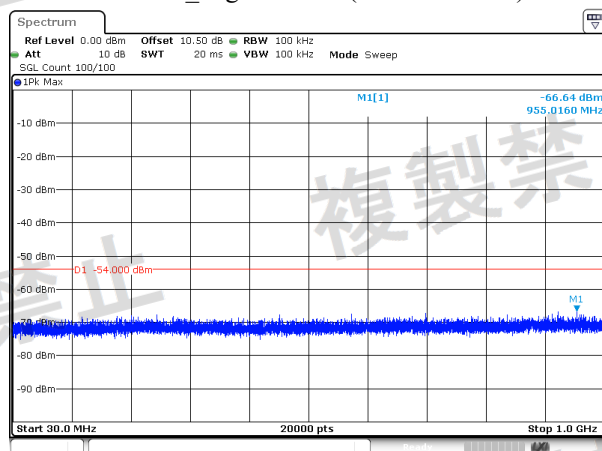
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Date: 10.NOV.2025 13:50:59

BLE 2M_Middle Channel(1GHz~12.5GHz)



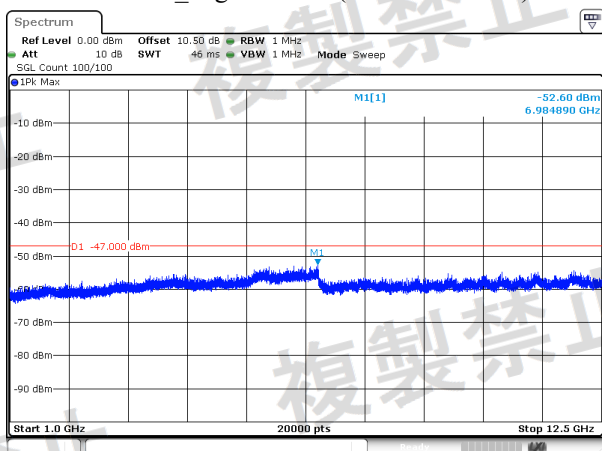
ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:51:26

BLE 2M_High Channel(30MHz~1GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:51:46

BLE 2M_High Channel(1GHz~12.5GHz)



ProjectNo.:2501Y11127E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 13:52:13

Interference Prevention Function**Test Information:**

Sample No.:	3BRX-2	Test Date:	2025/11/10
Test Site:	RF	Test Mode:	Communicating
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	26.2	Relative Humidity: (%)	53	ATM Pressure: (kPa)	100.7
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MAC address: C3 00 00 49 6E 6C

CONSTRUCTION PROTECTION CONFIRMATION

Limit

The high-frequency section and modulation section of the radio equipment except for the antenna system shall not be capable of being opened easily.

Confirmation Result

The EUT has screws which can't be opened easily, please see the EUT photos.

EUT PHOTOGRAPHS

Please refer to the attachment 2501Y11127E-RF-EXP External photo and 2501Y11127E-RF-INP Internal photo.

TEST SETUP PHOTOGRAPHS

Please refer to the attachment 2501Y11127E-RF-07A-TSP Test Setup photo.

****END OF REPORT****